

Fig. 1b

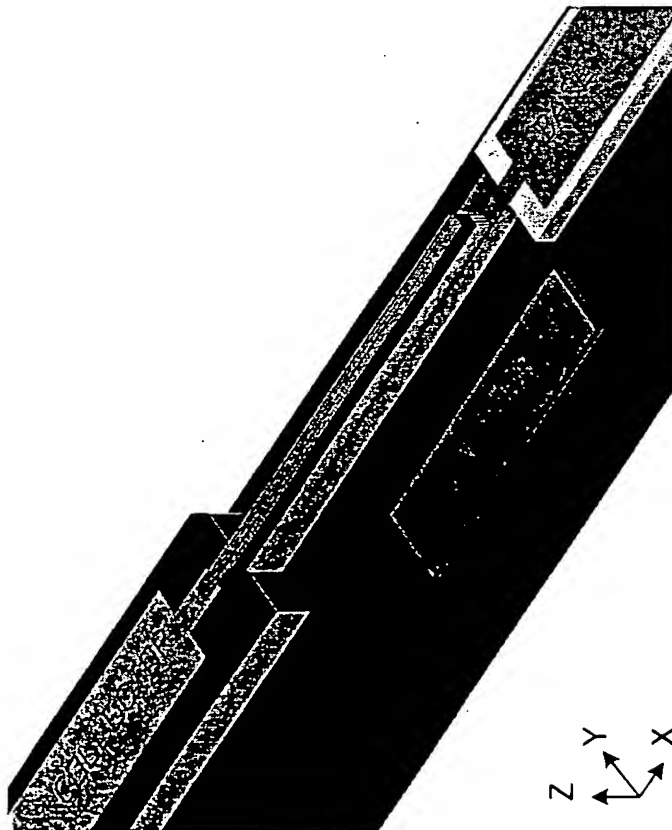


Fig. 1a

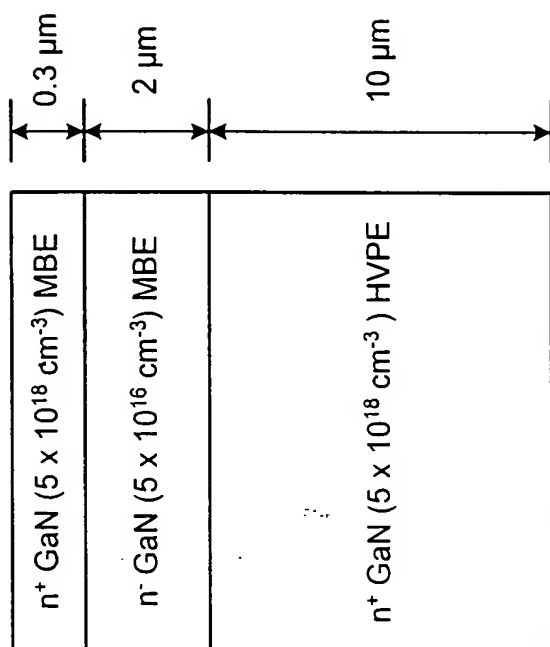


Fig. 2a

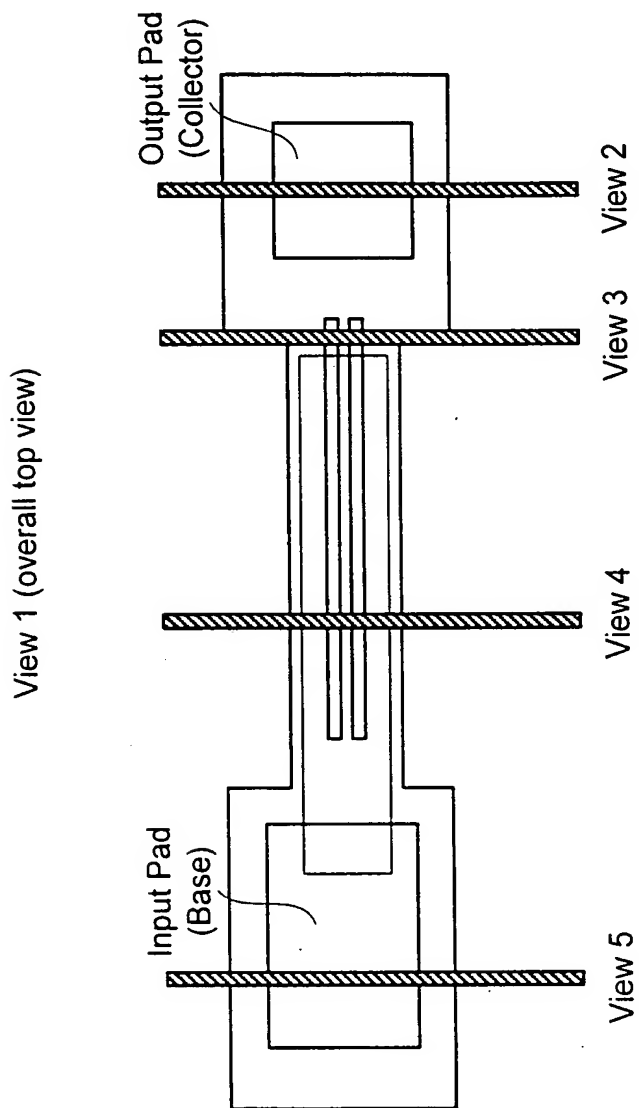


Fig. 2b

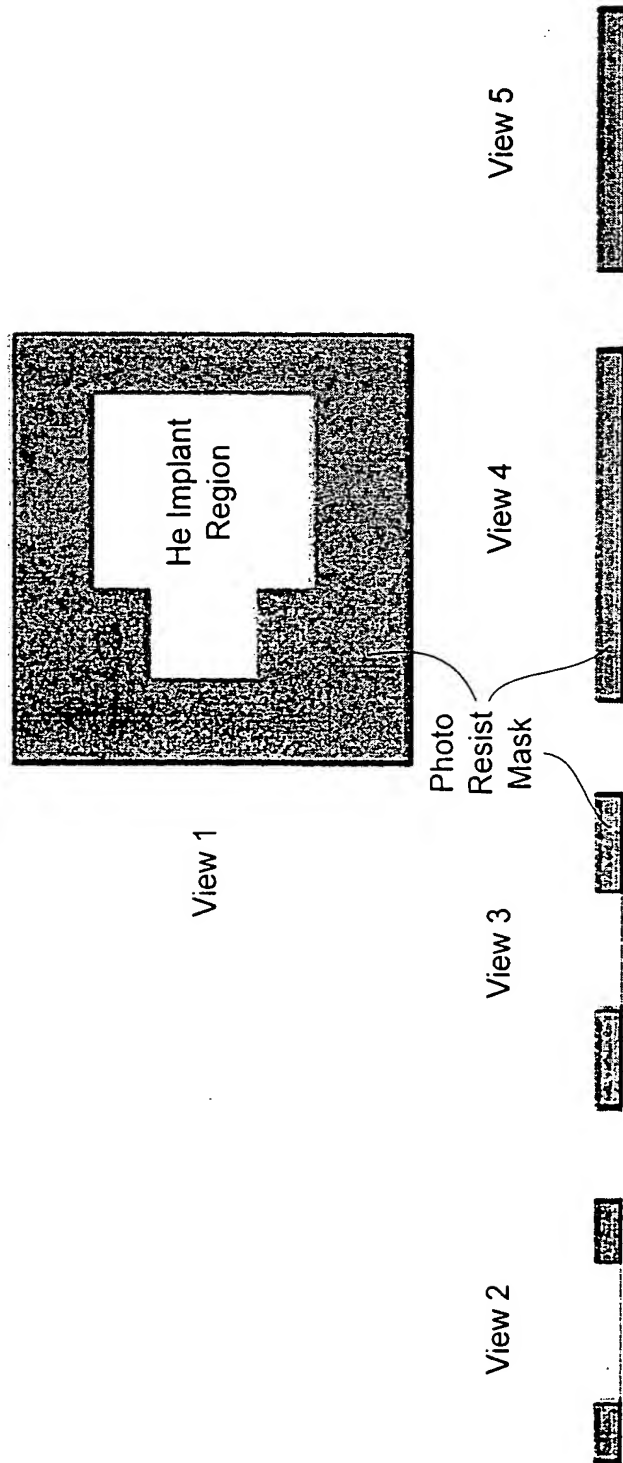
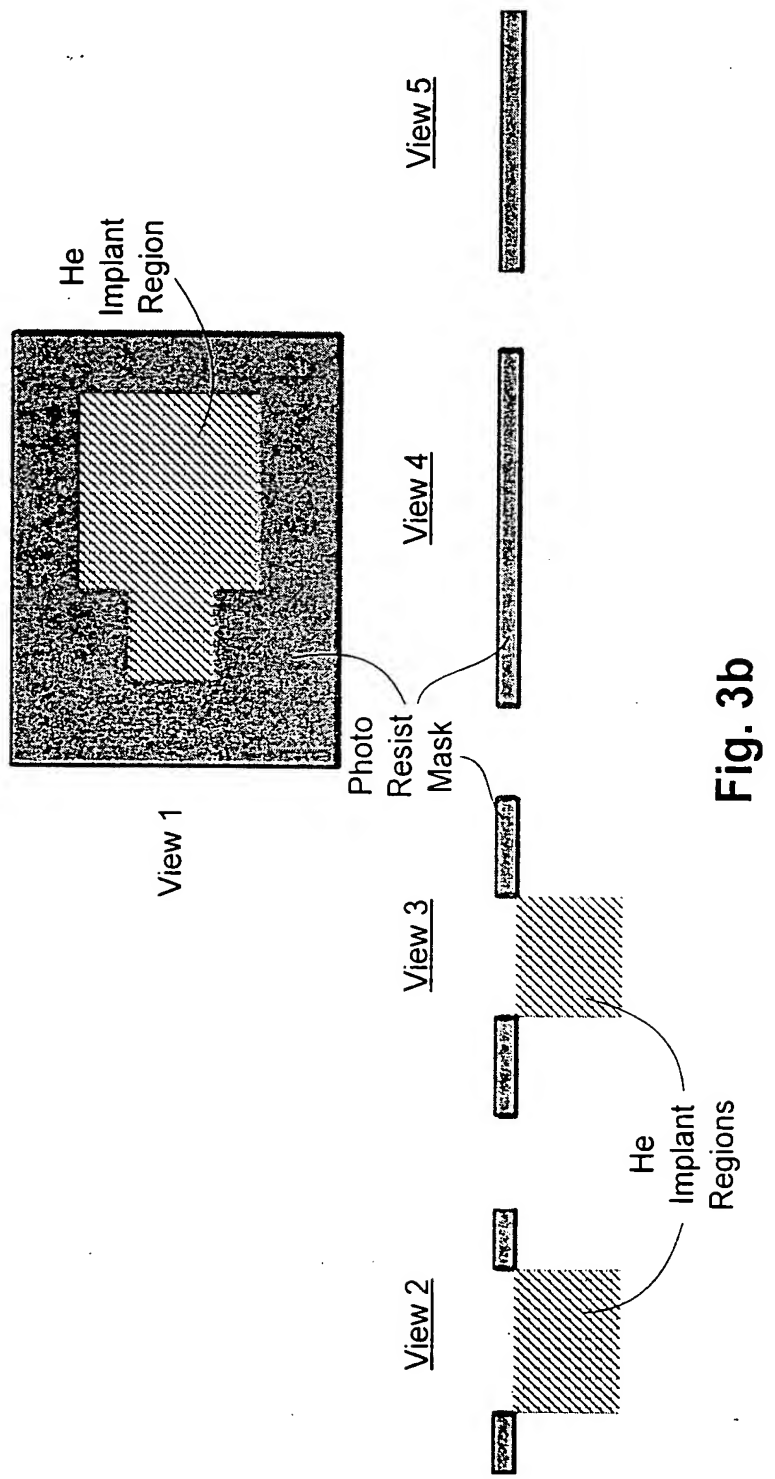
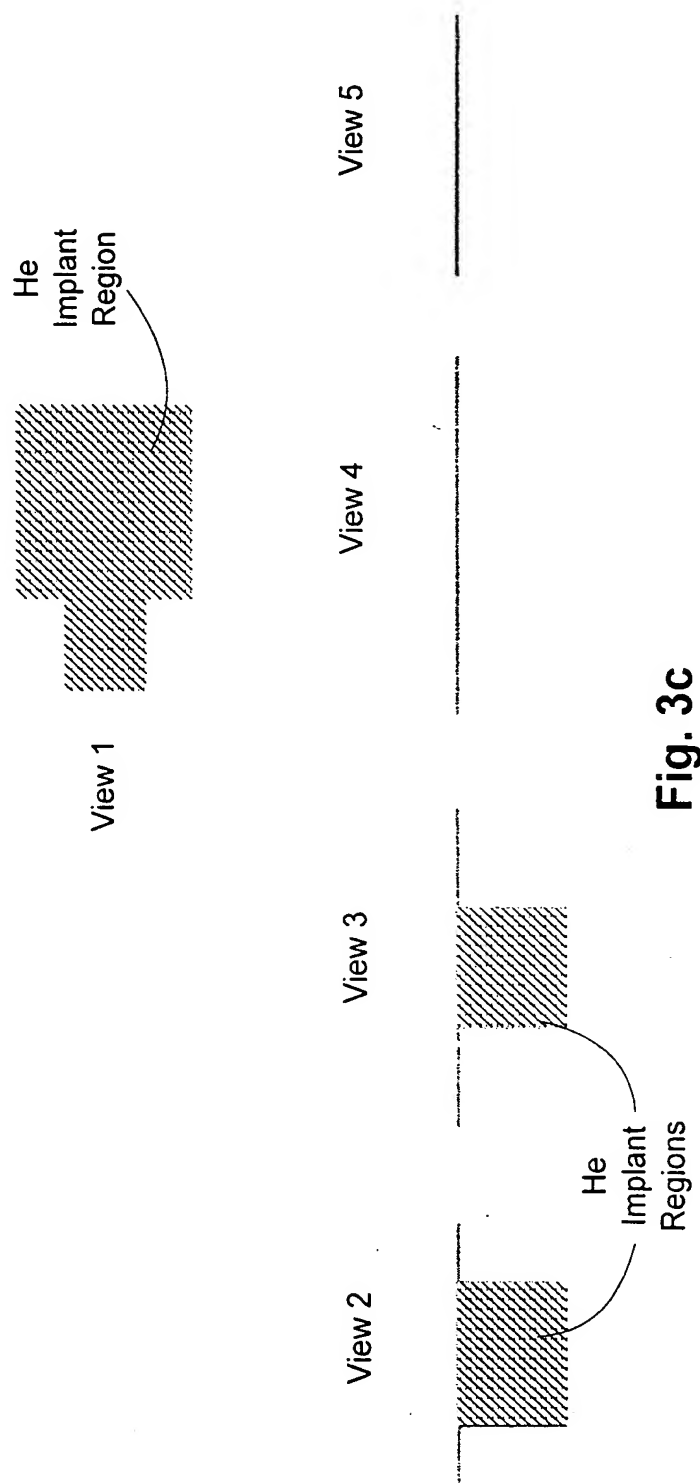


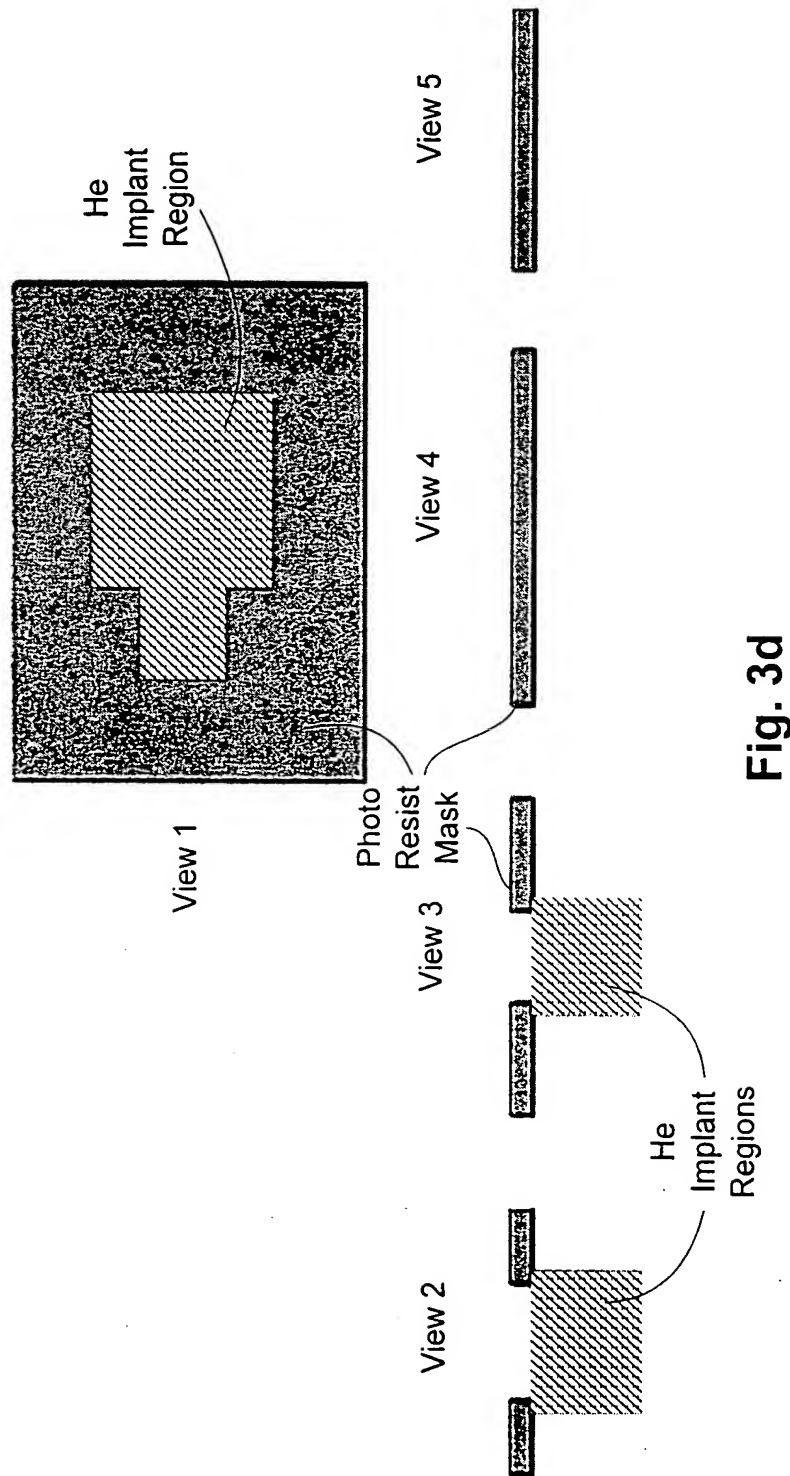
Fig. 3a



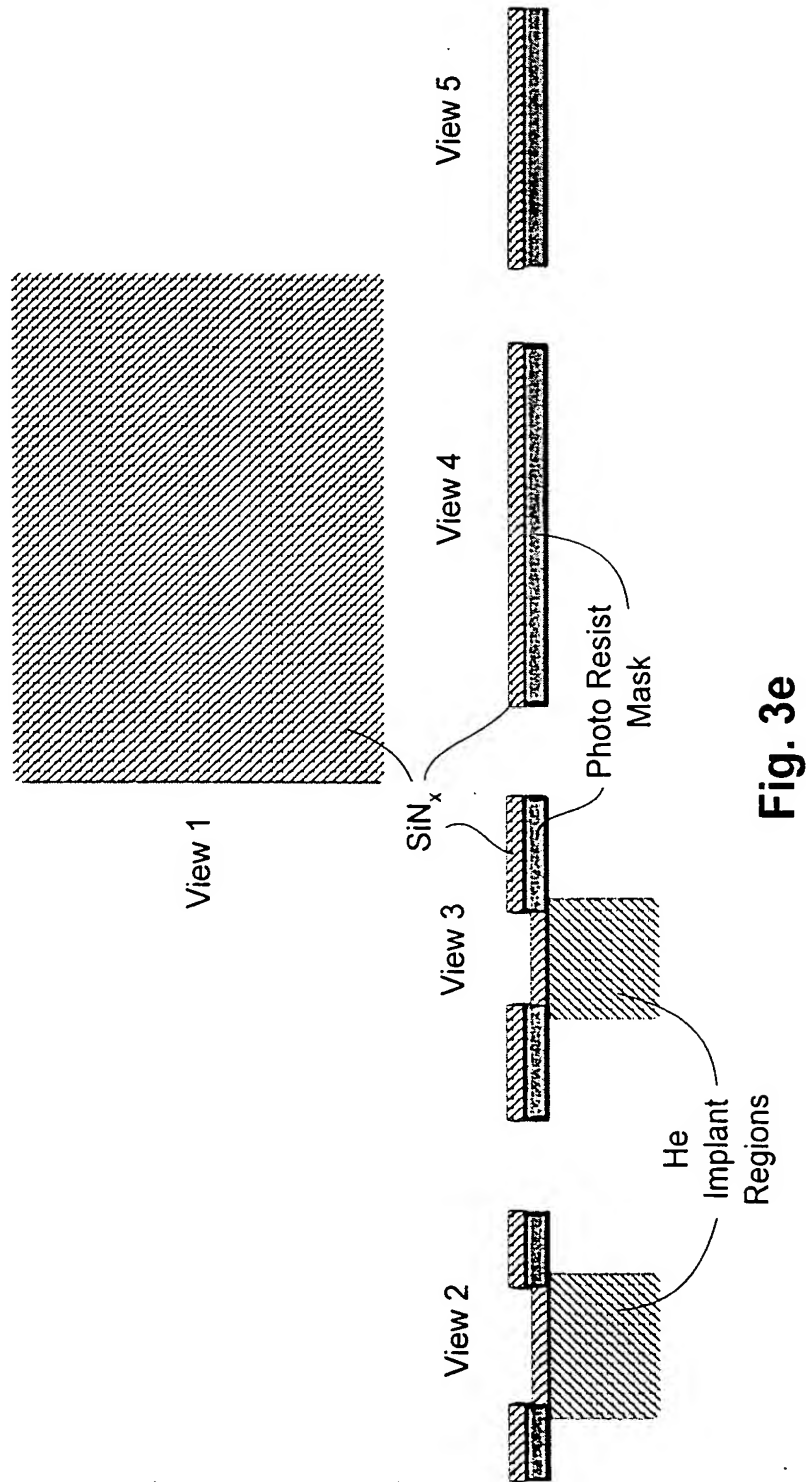
6/43

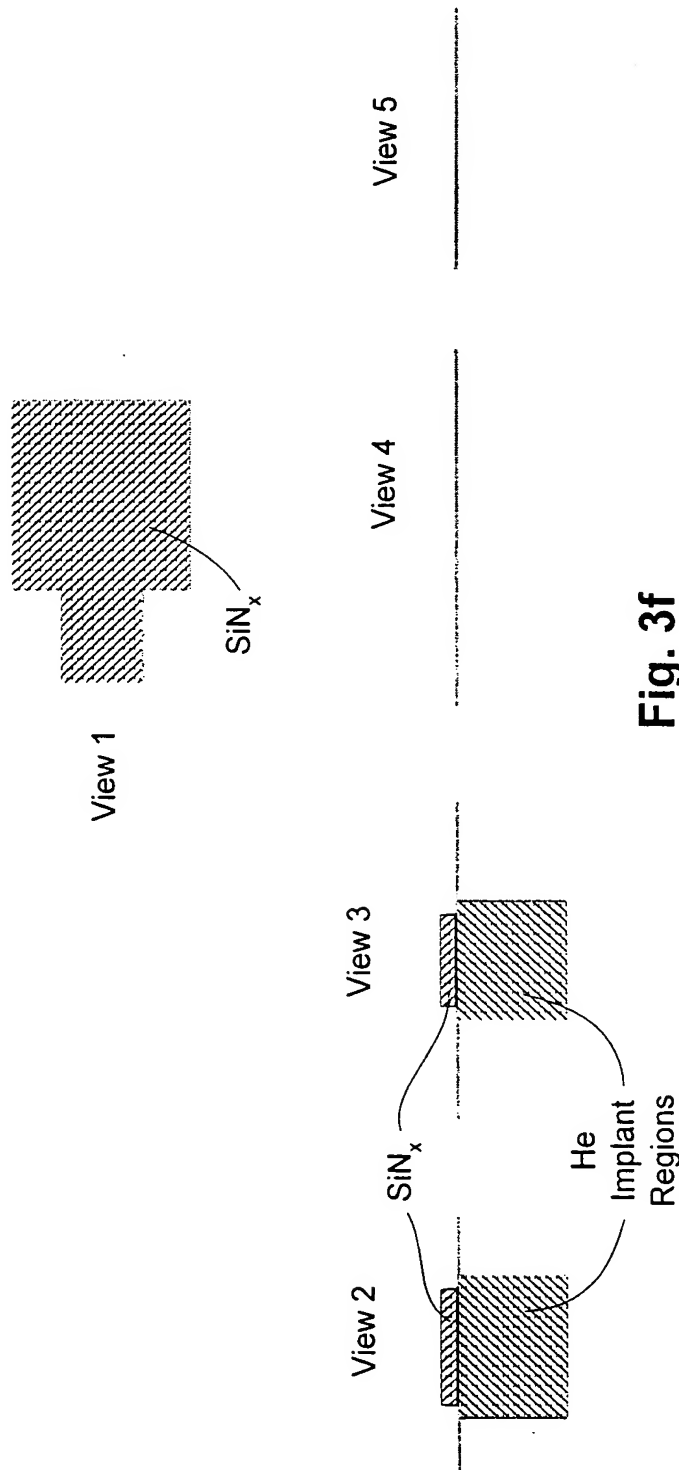


7/43

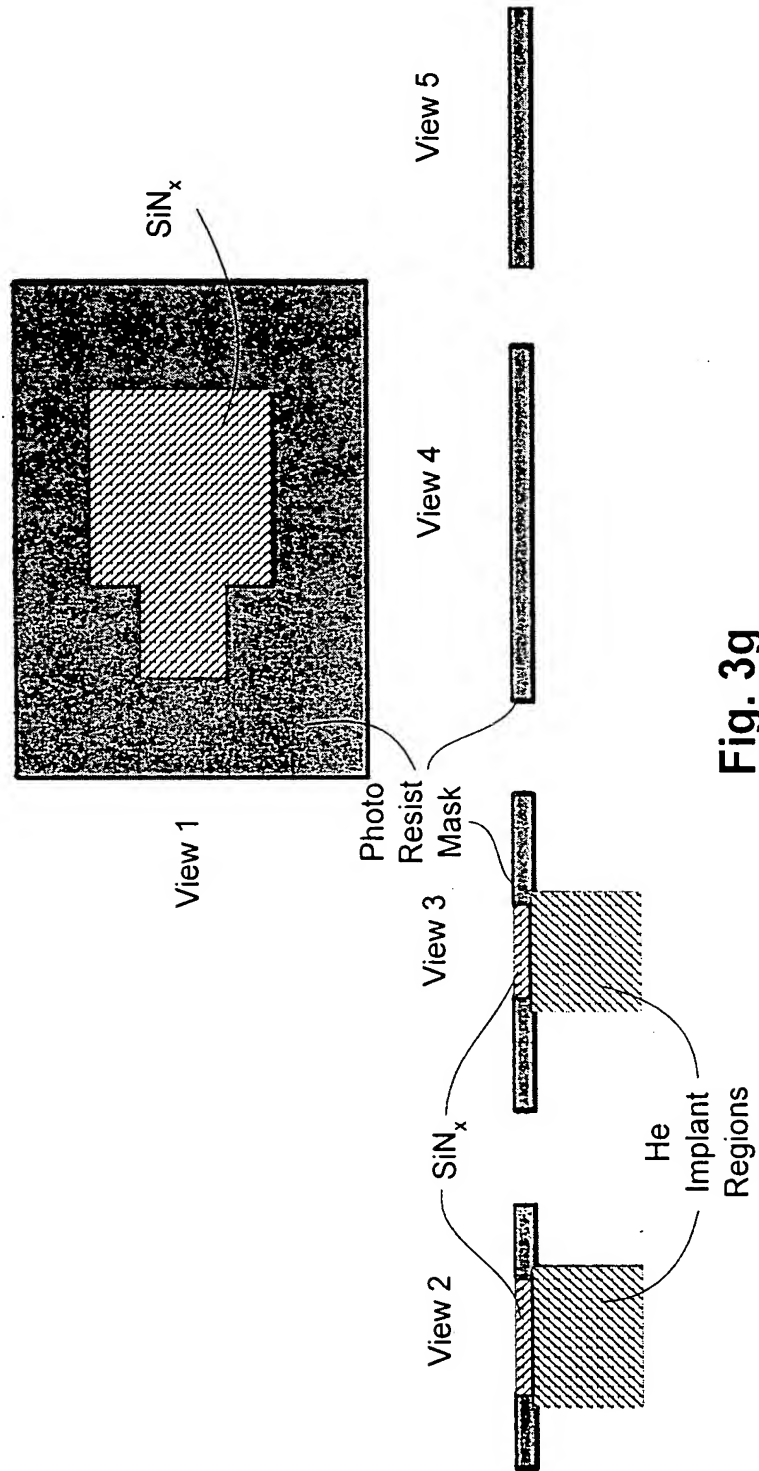


8/43





10/43



11/43

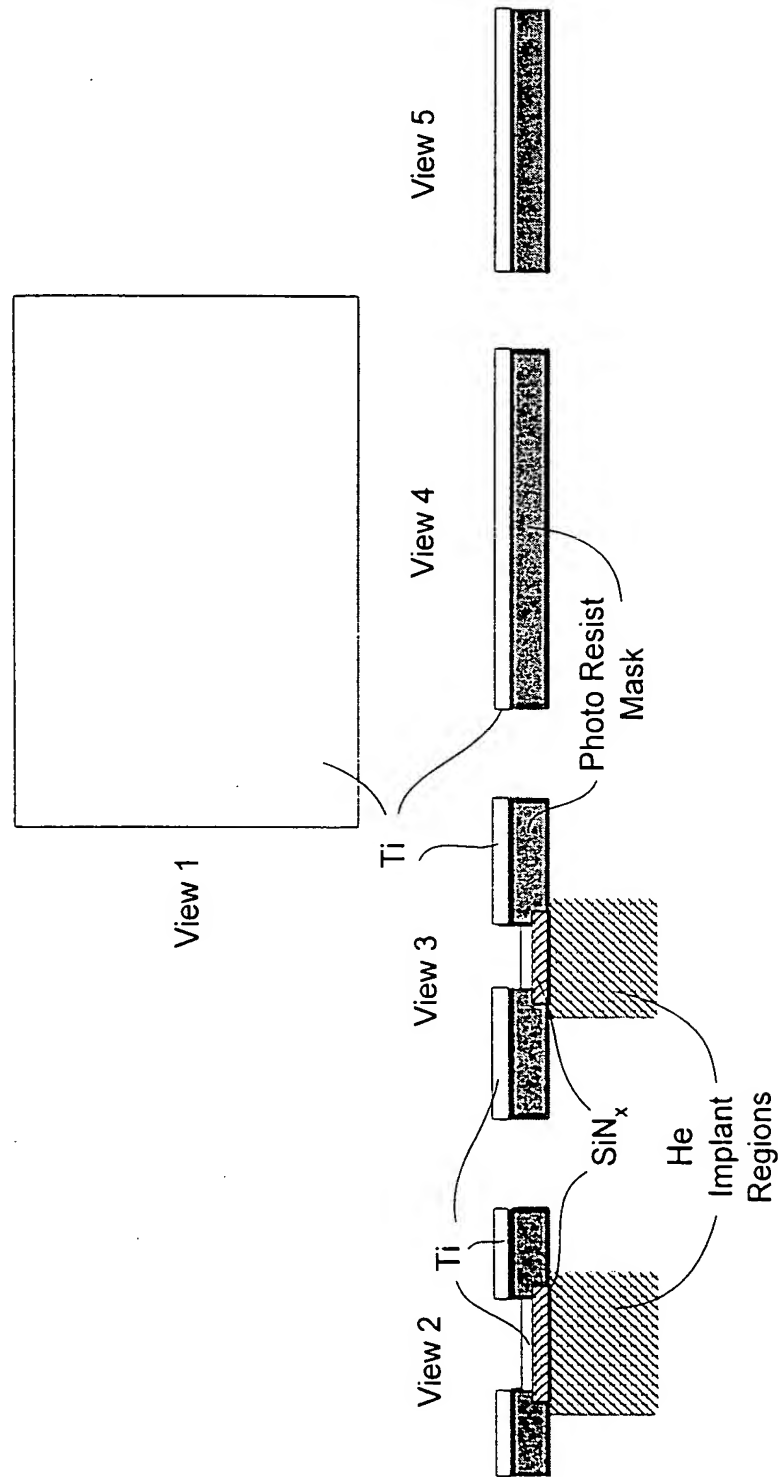
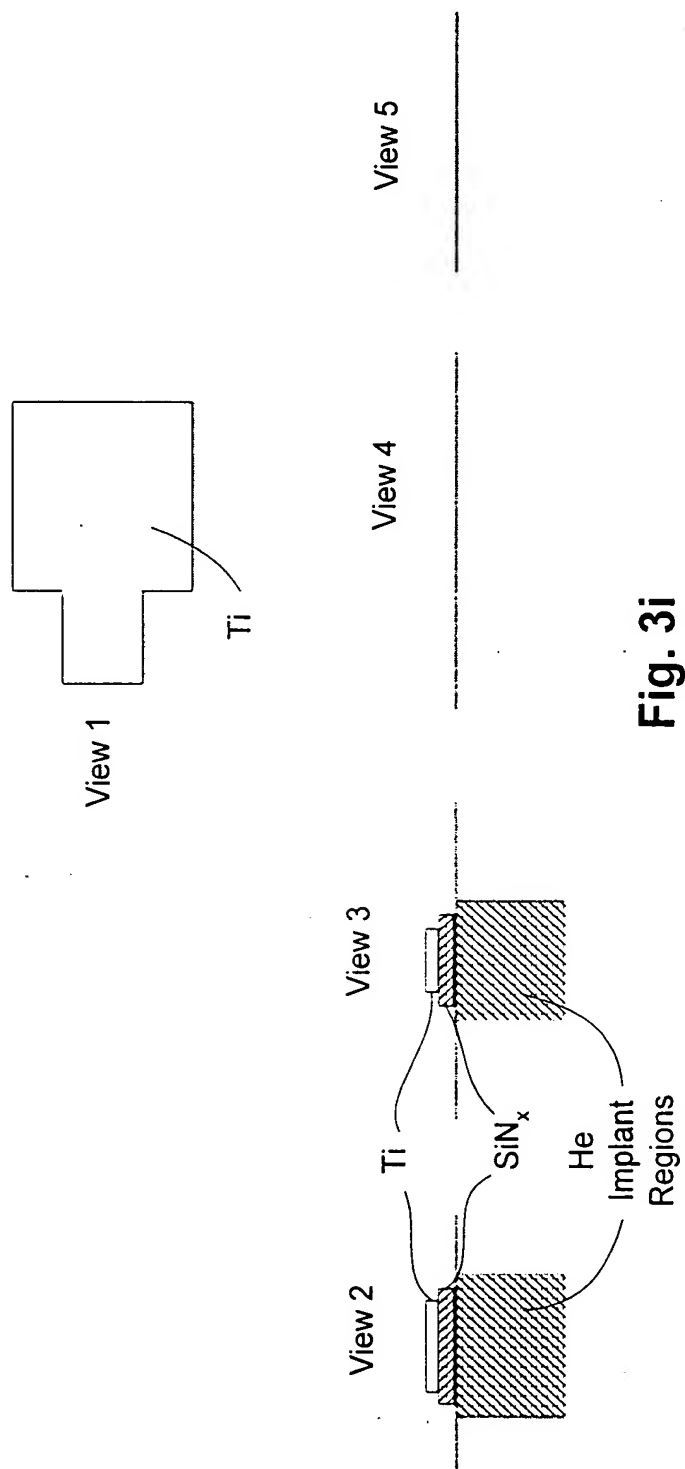
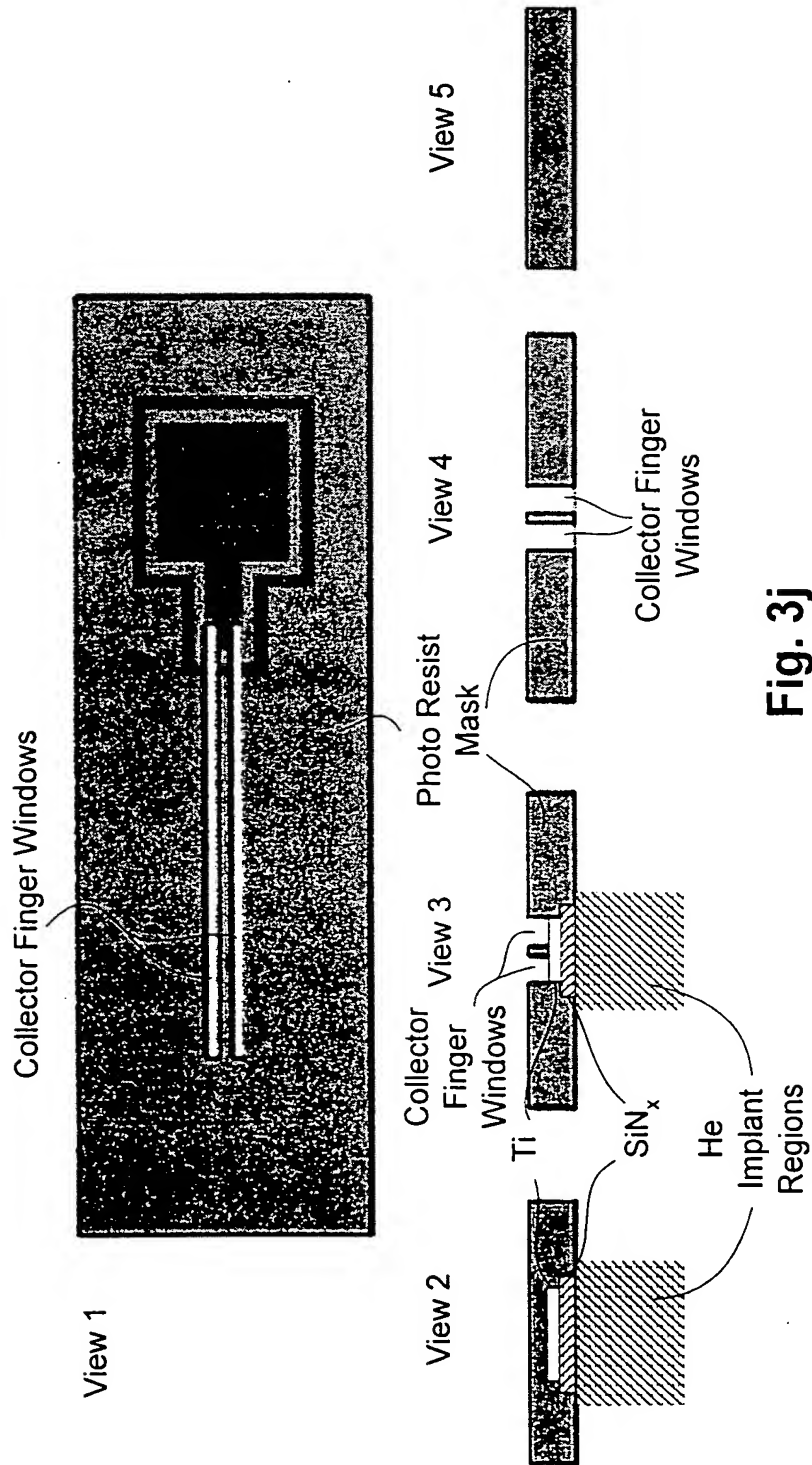


Fig. 3h

12/43





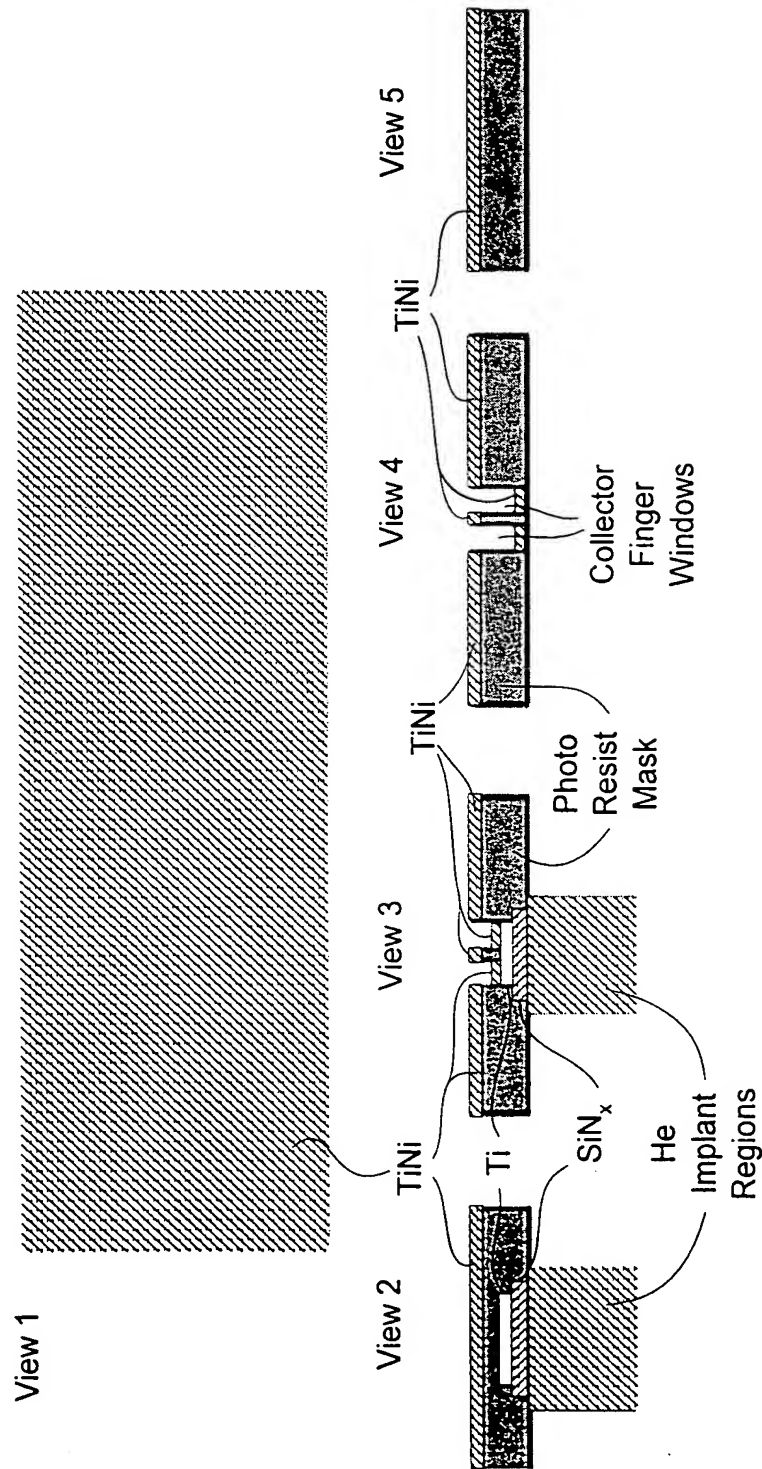


Fig. 3k

15/43

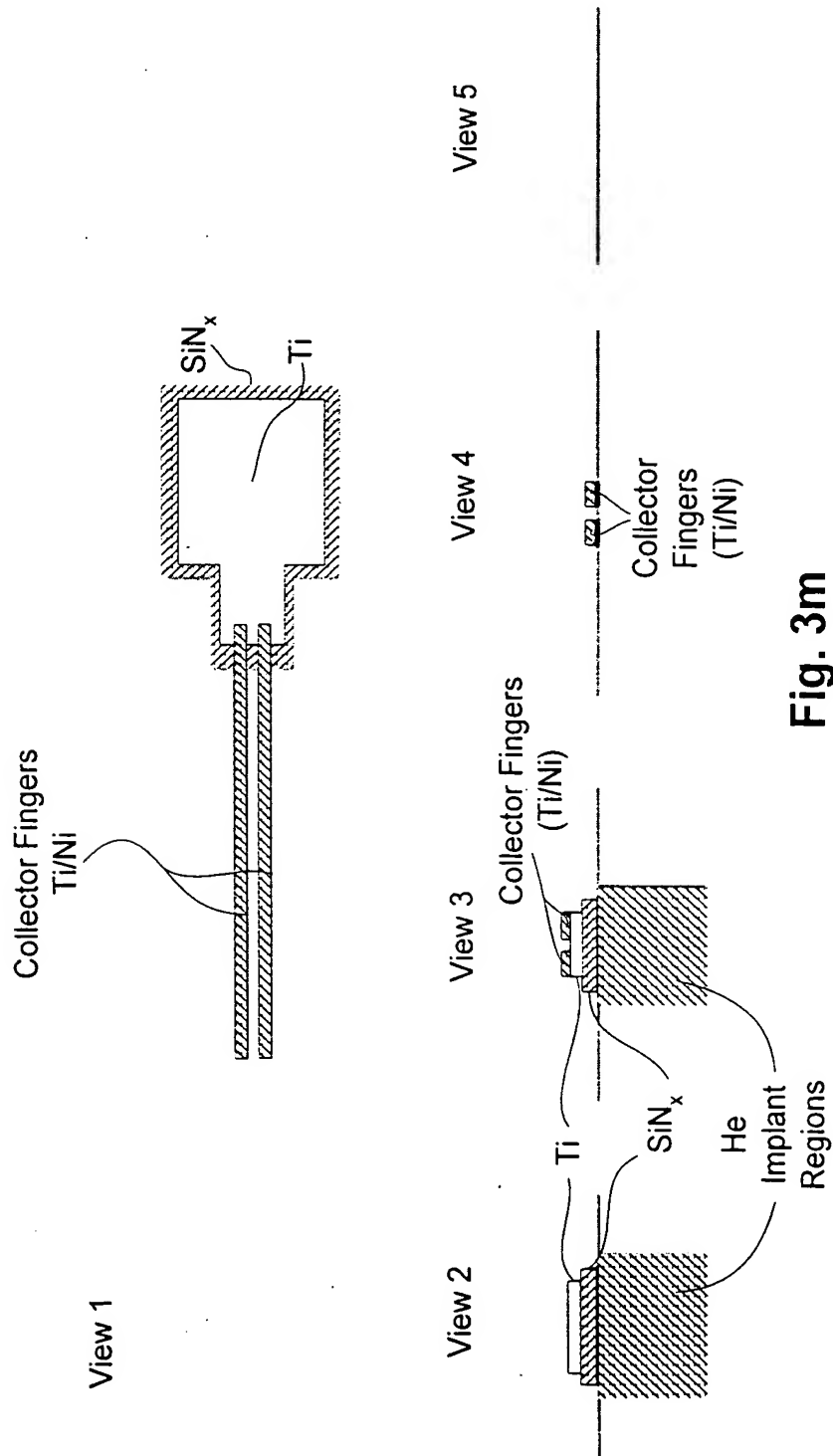
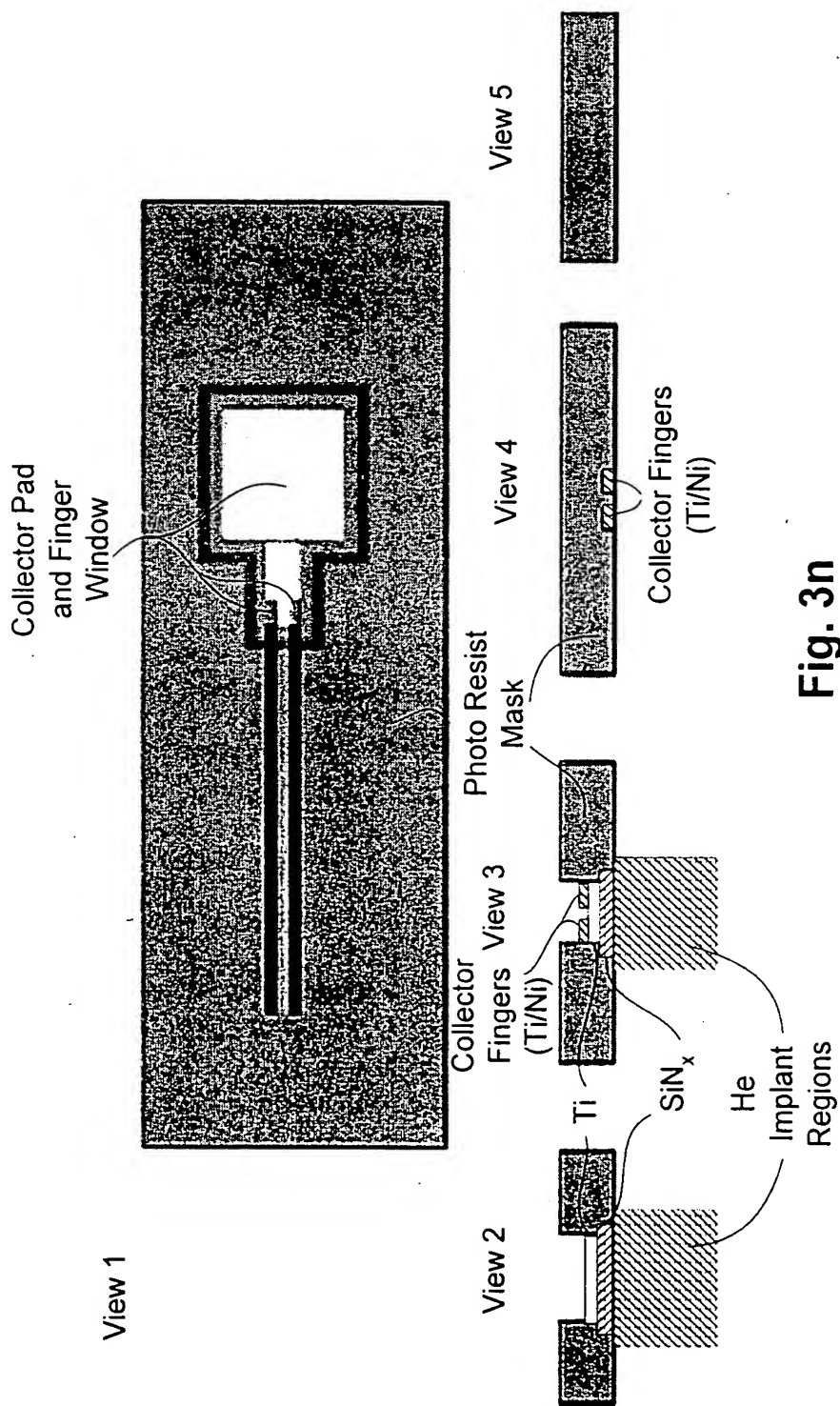
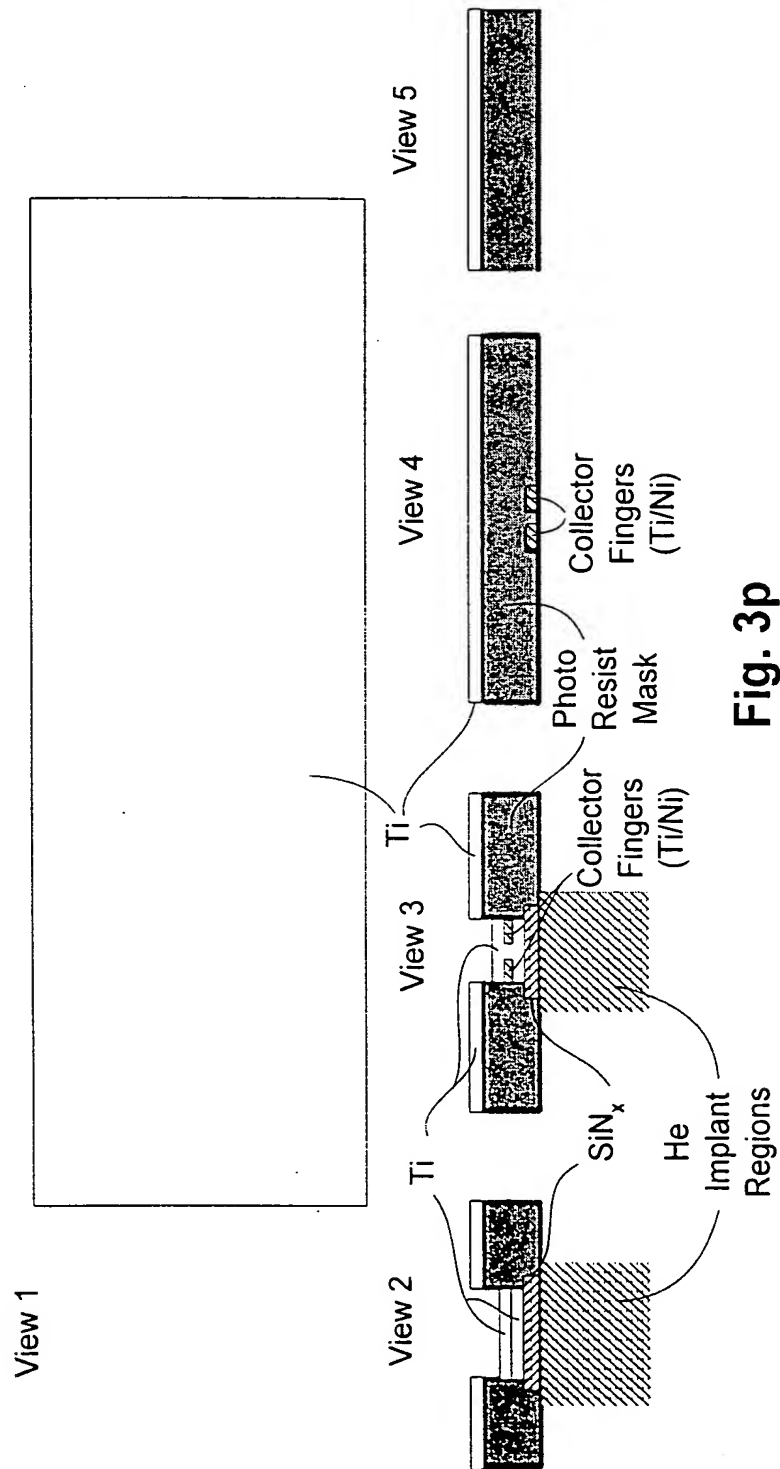


Fig. 3m





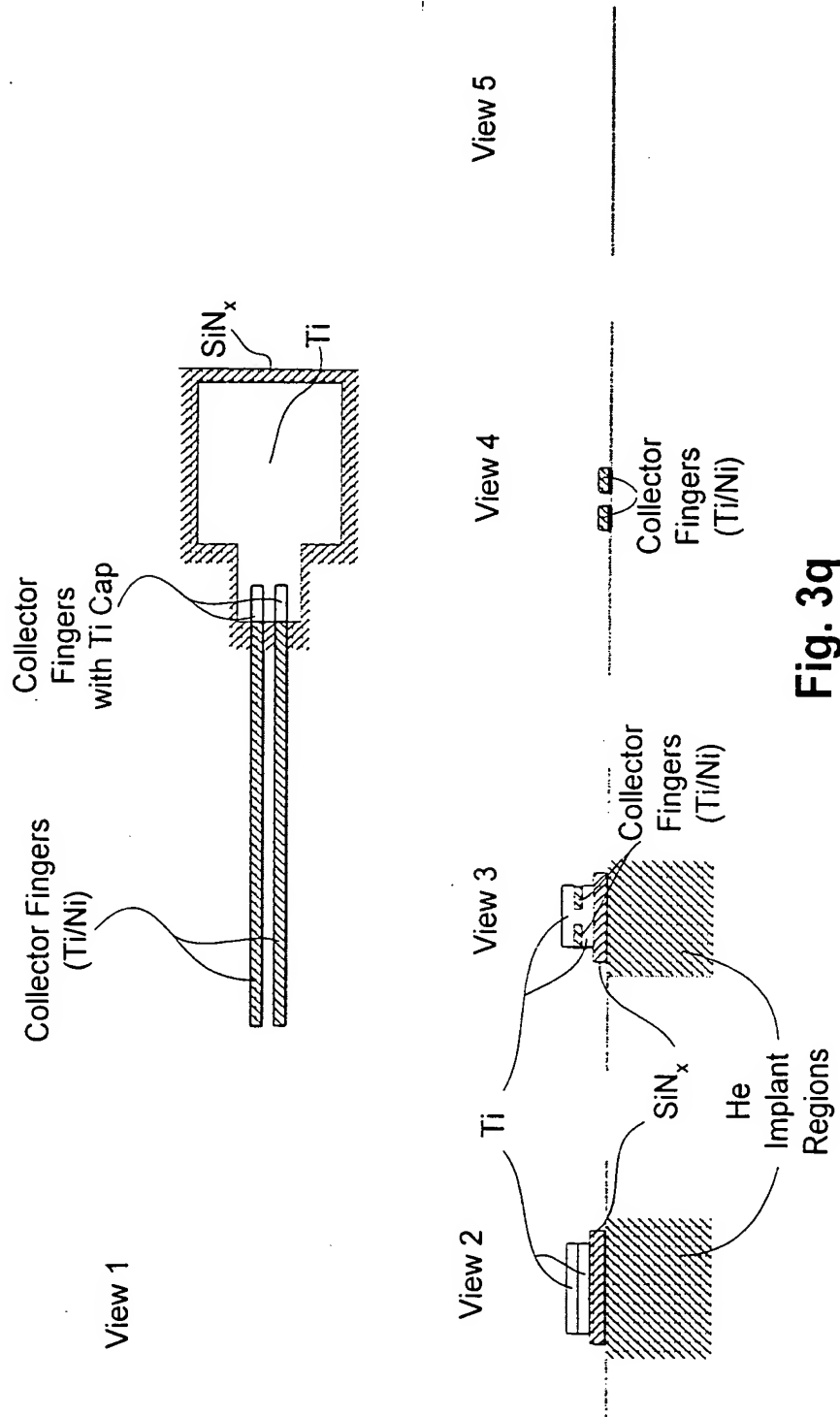


Fig. 3a

19/43

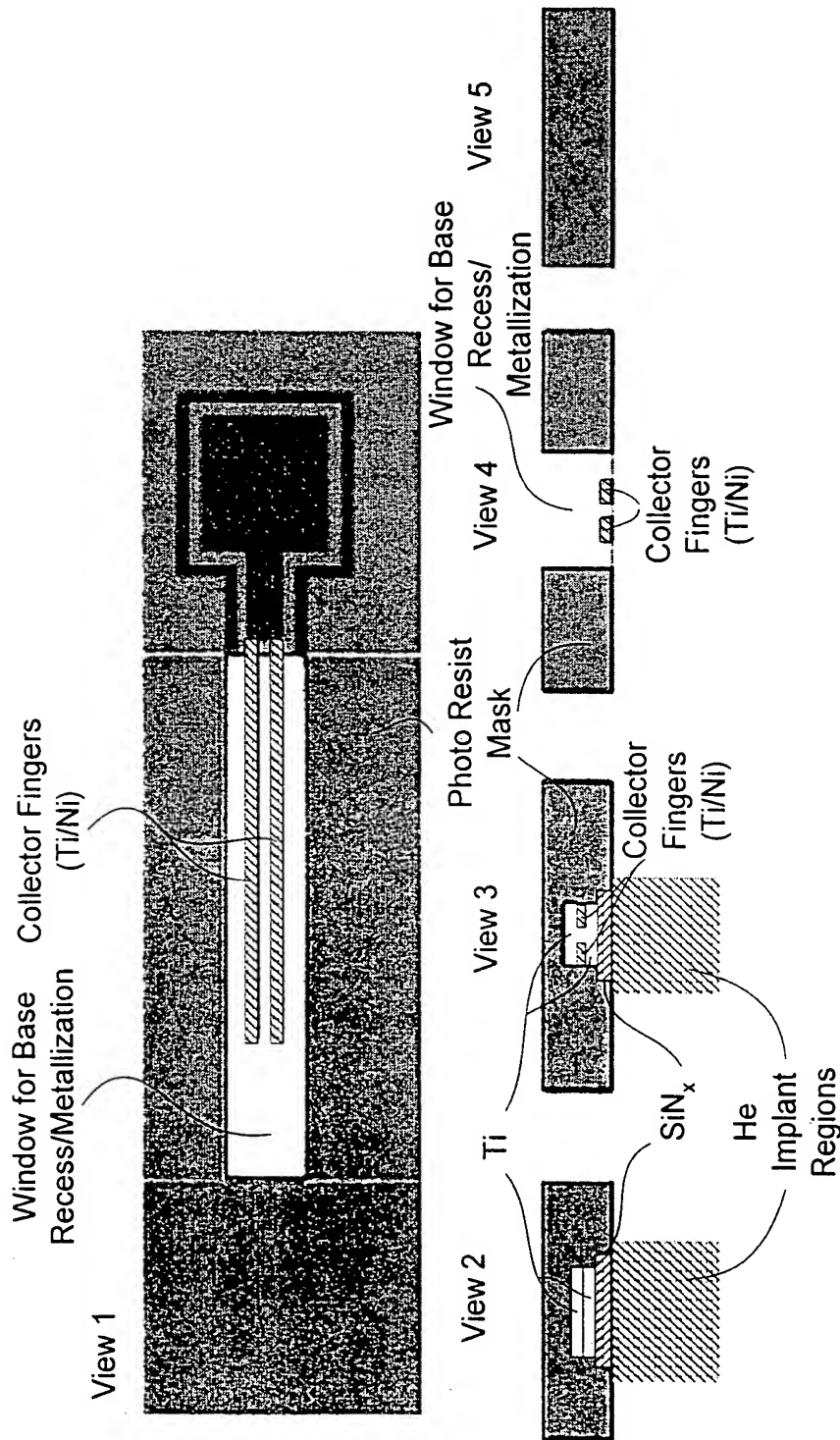


Fig. 3r

20/43

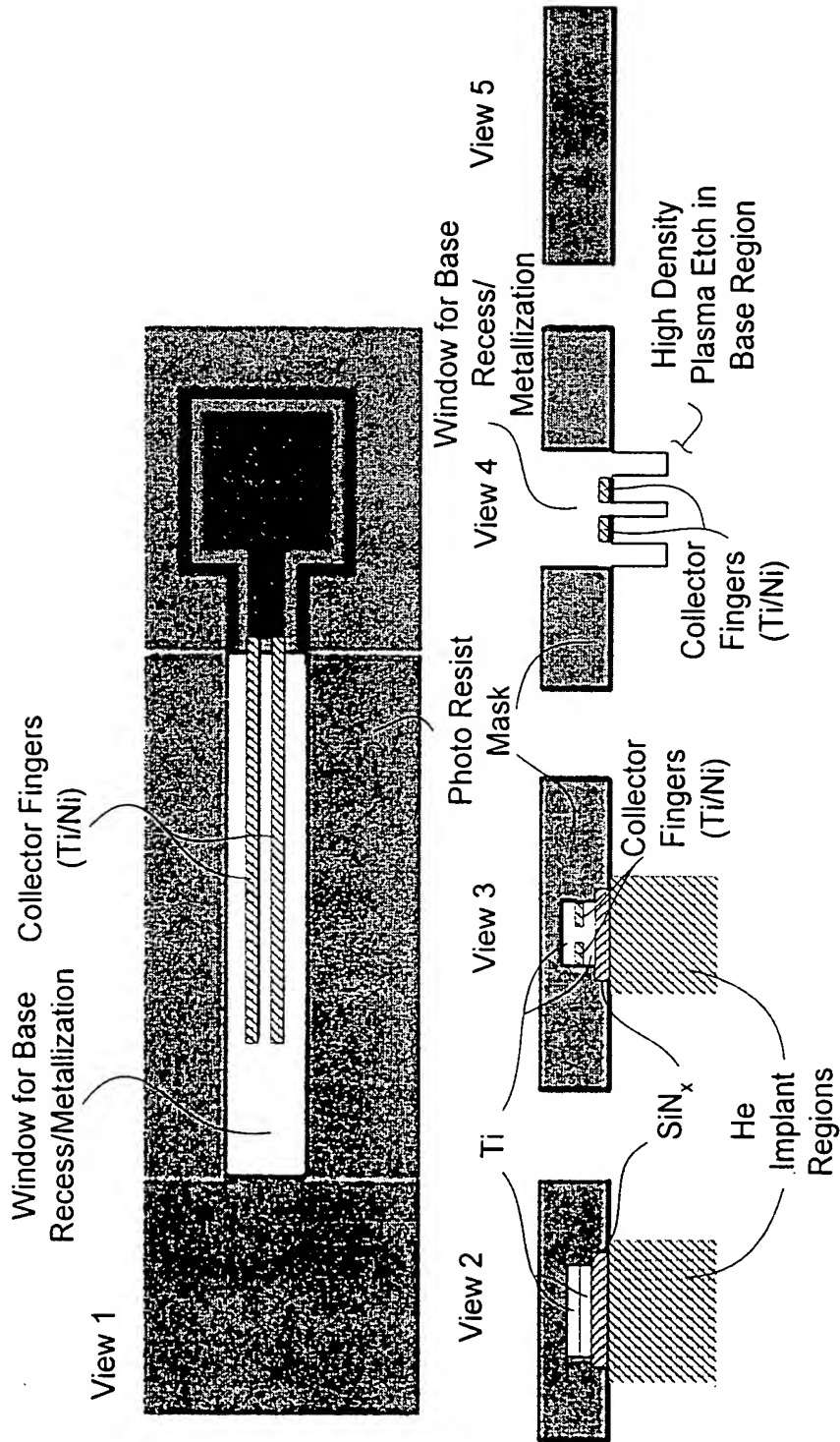


Fig. 3s

21/43

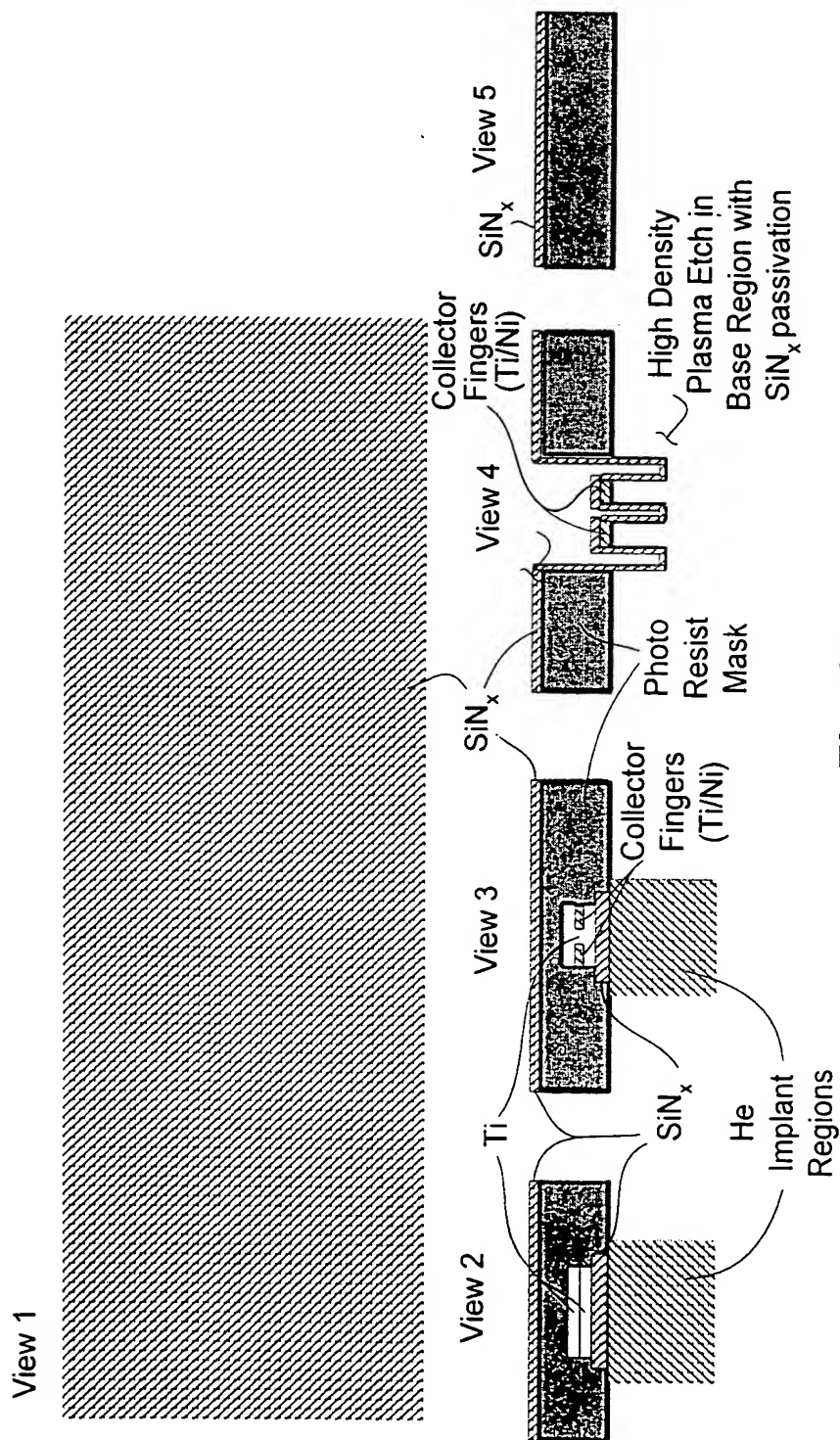


Fig. 3t

22/43

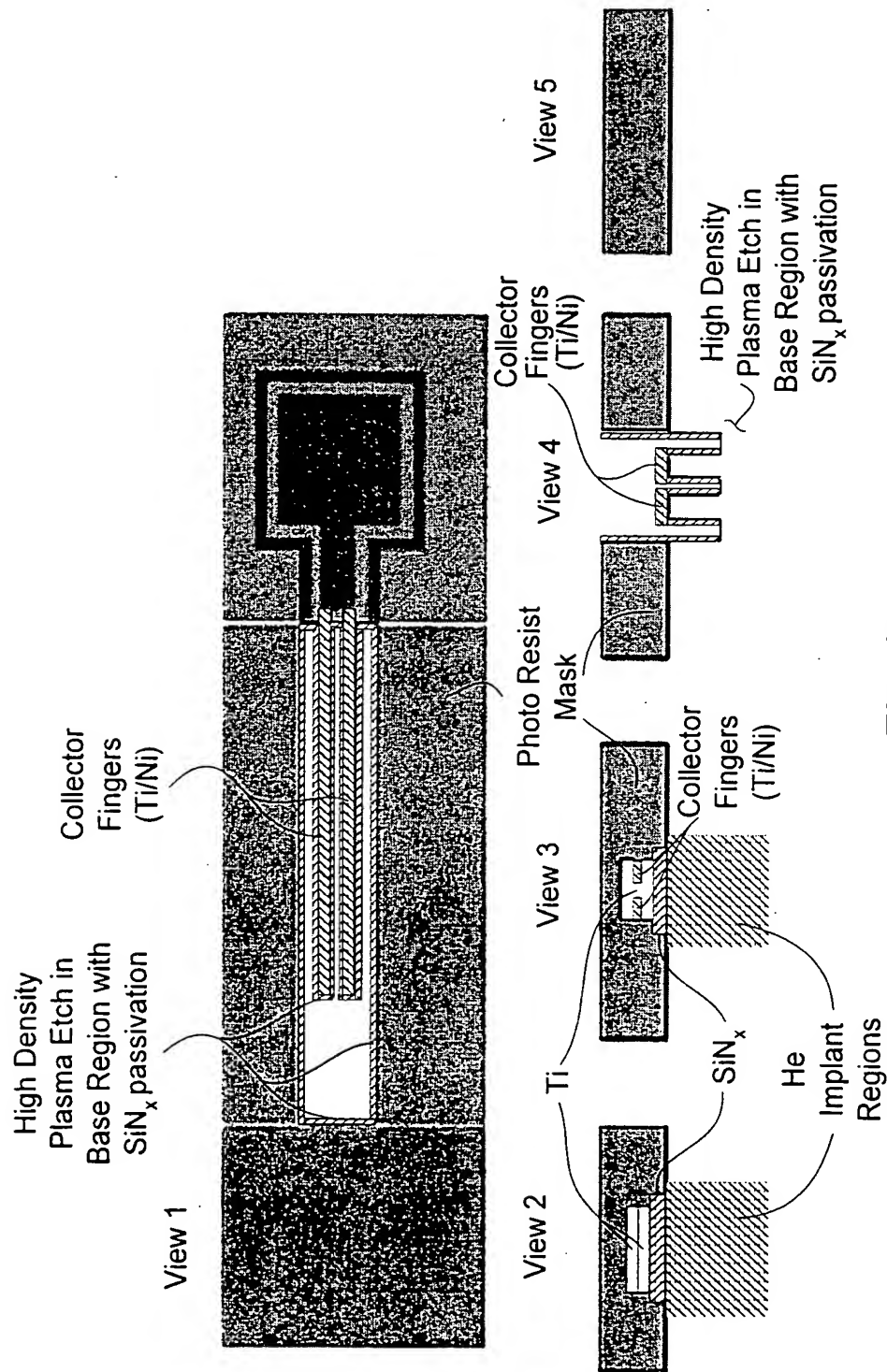


Fig. 3u

23/43

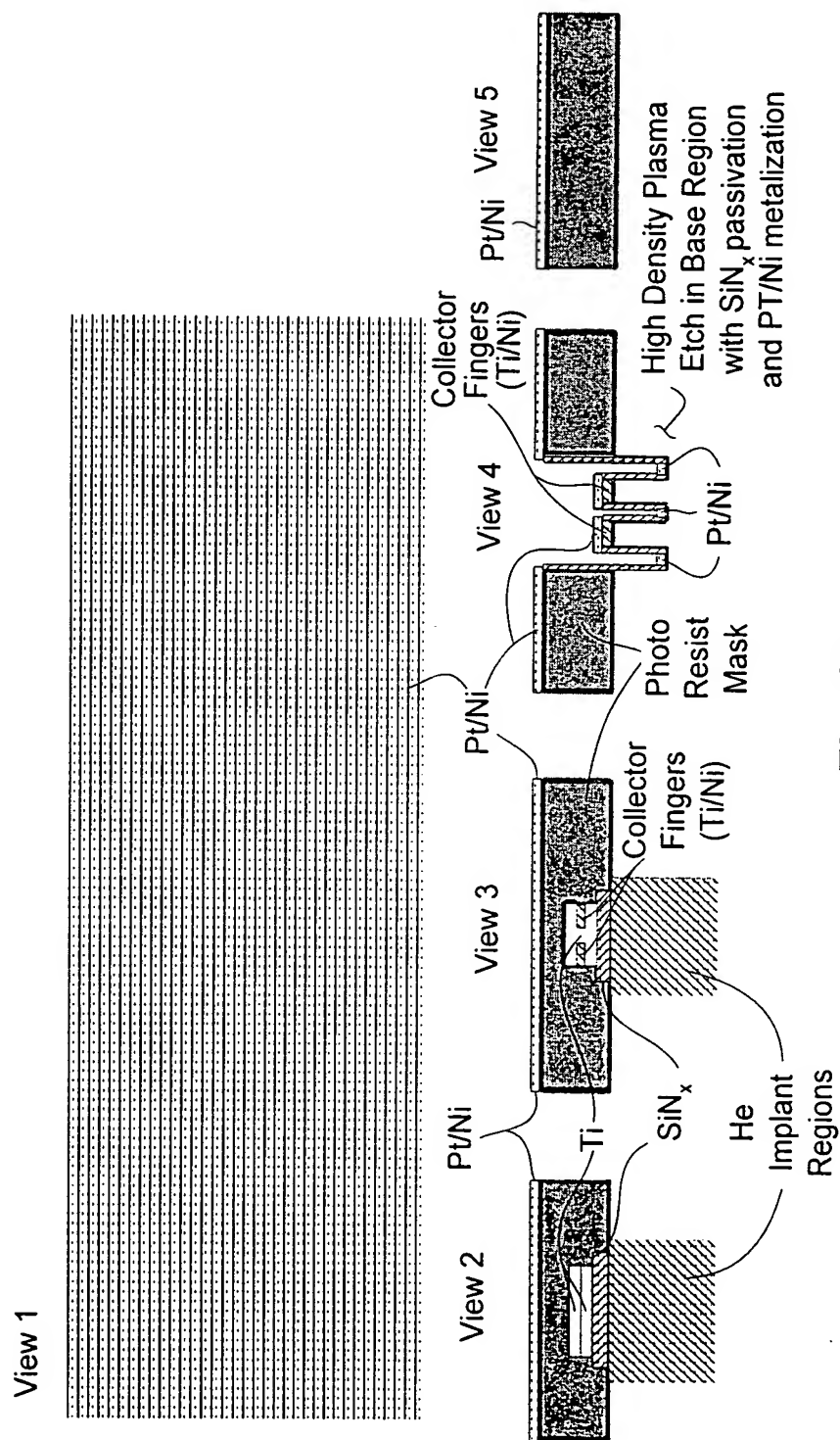


Fig. 3v

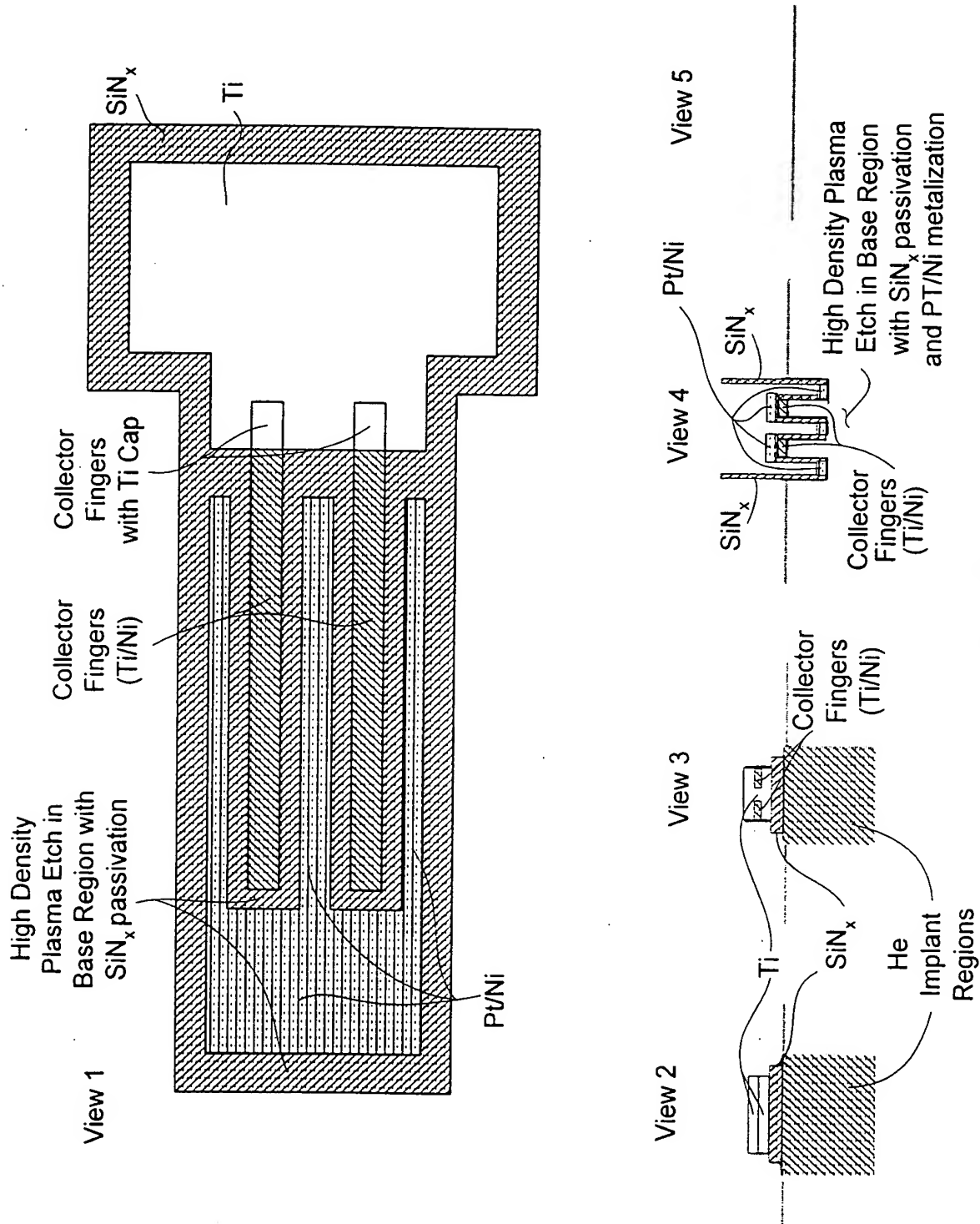


Fig. 3w

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 PCT – Customer # 42716

25/43

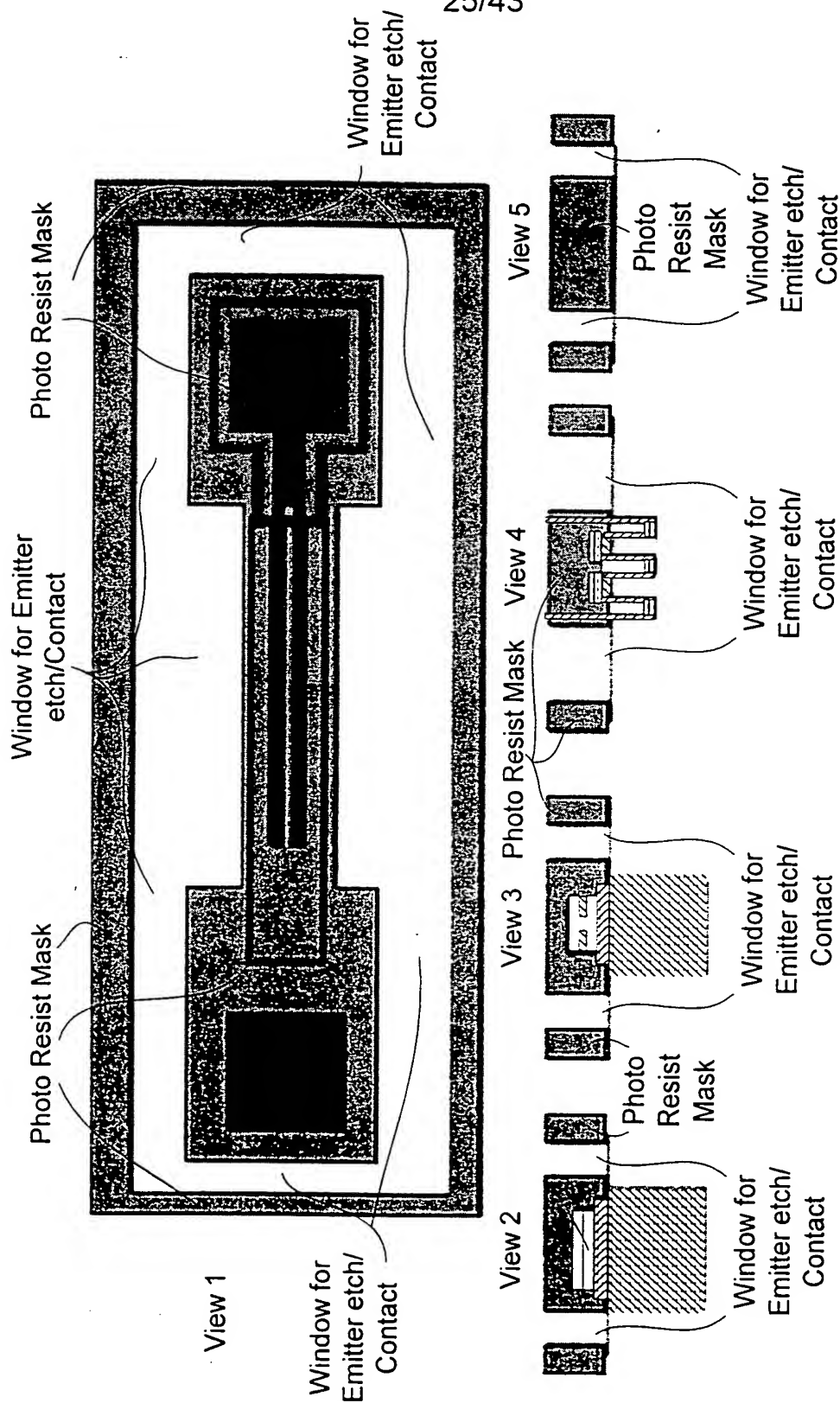


Fig. 3X

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26/43

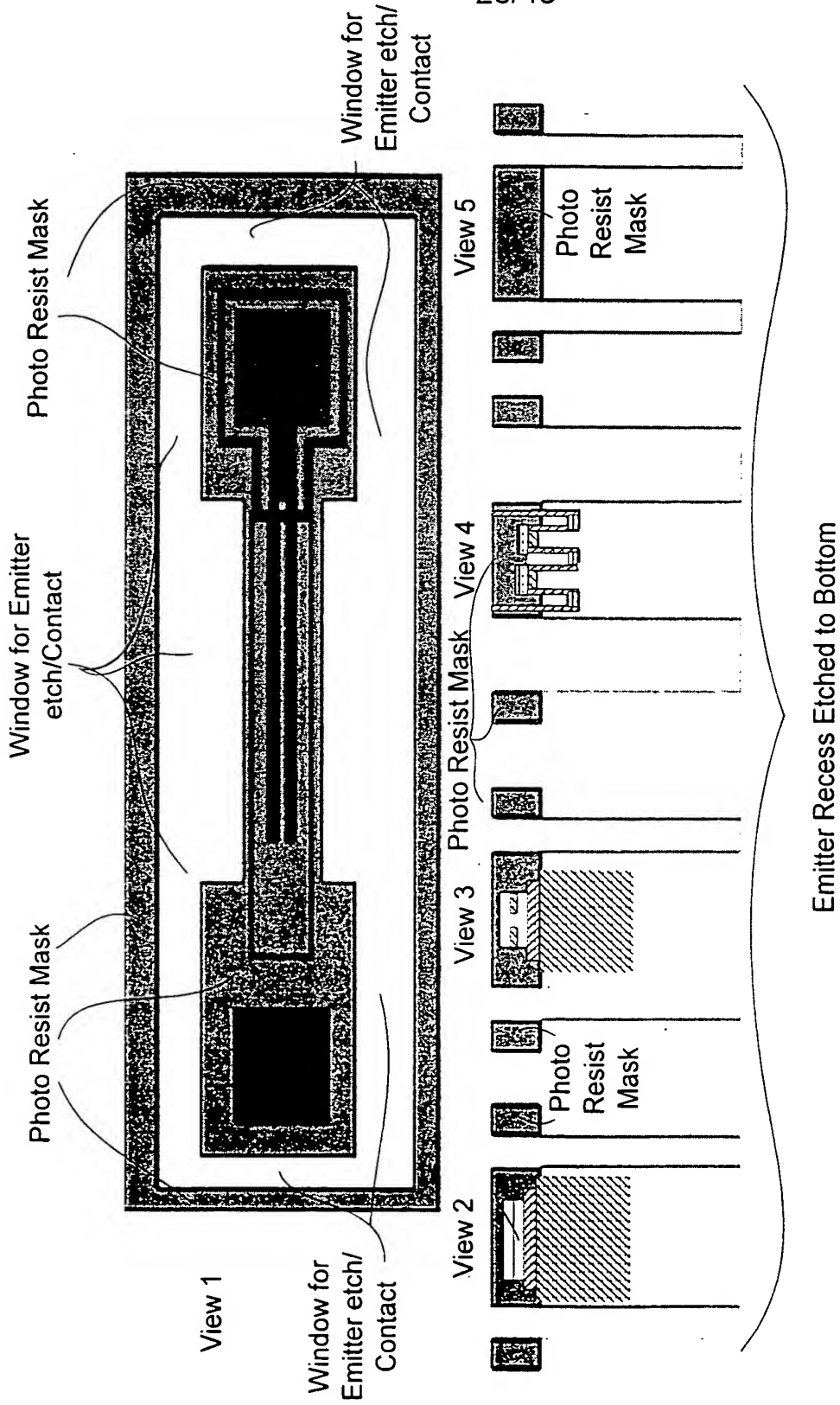


Fig. 3y

27/43

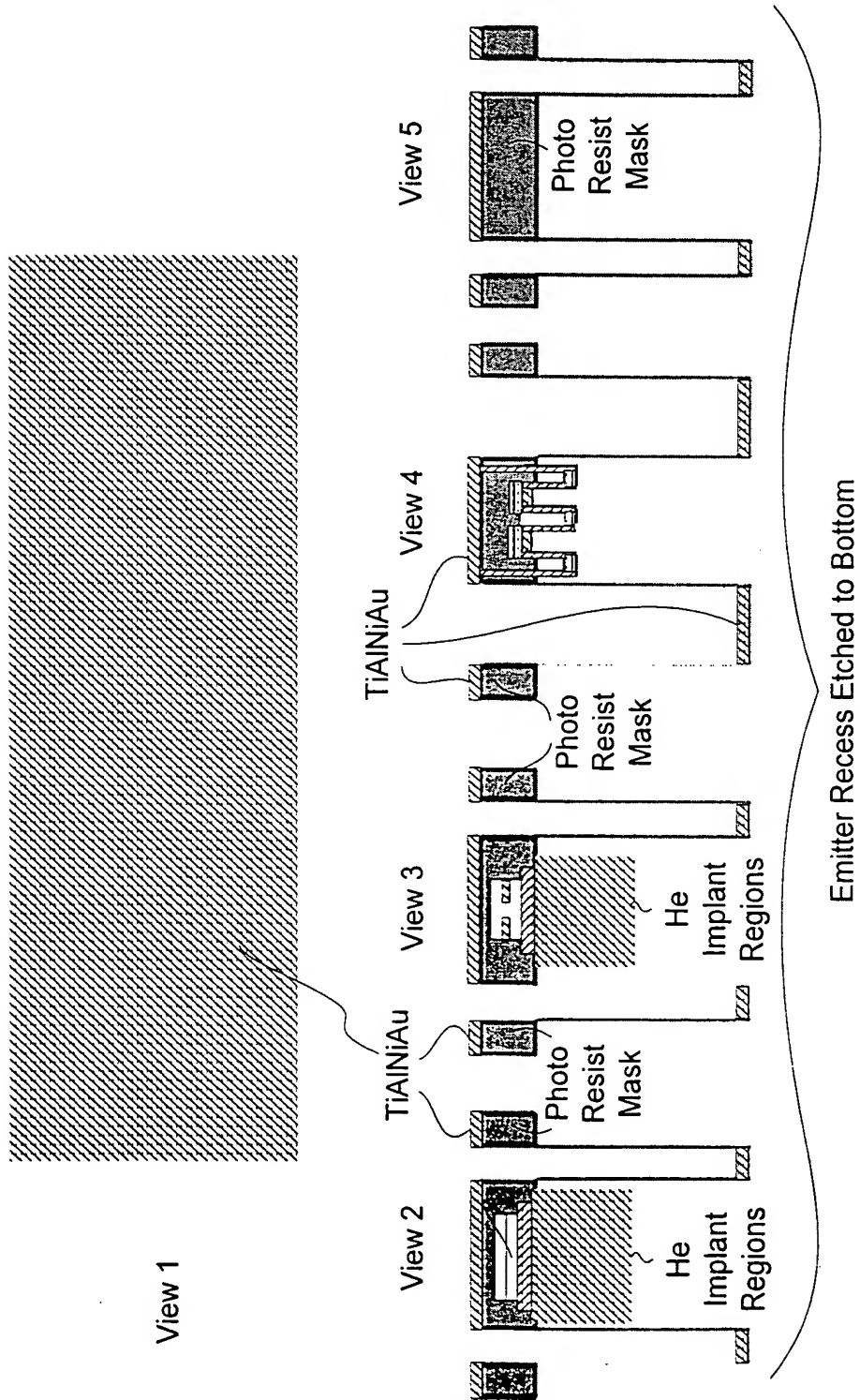


Fig. 3z

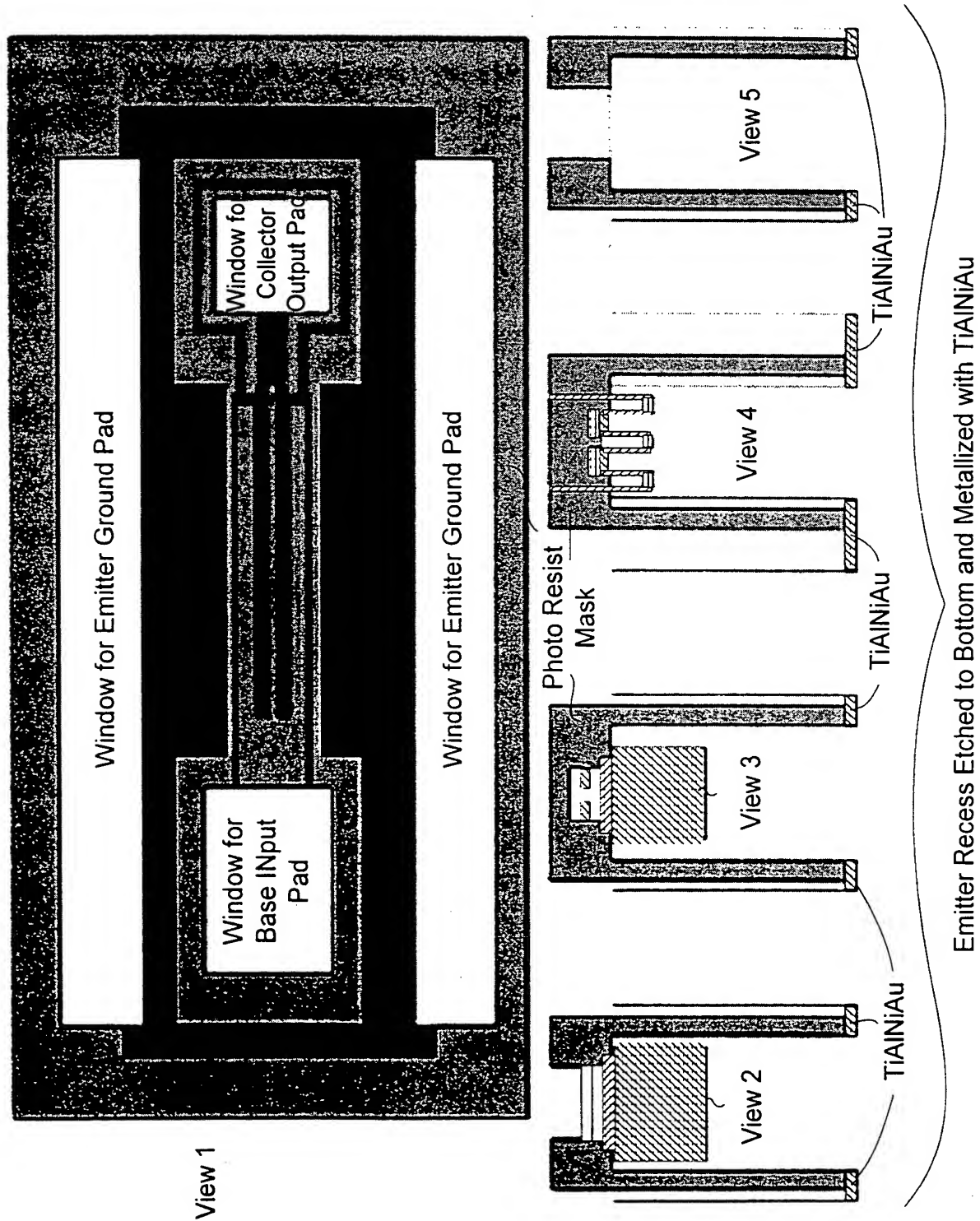


Fig. 3bb

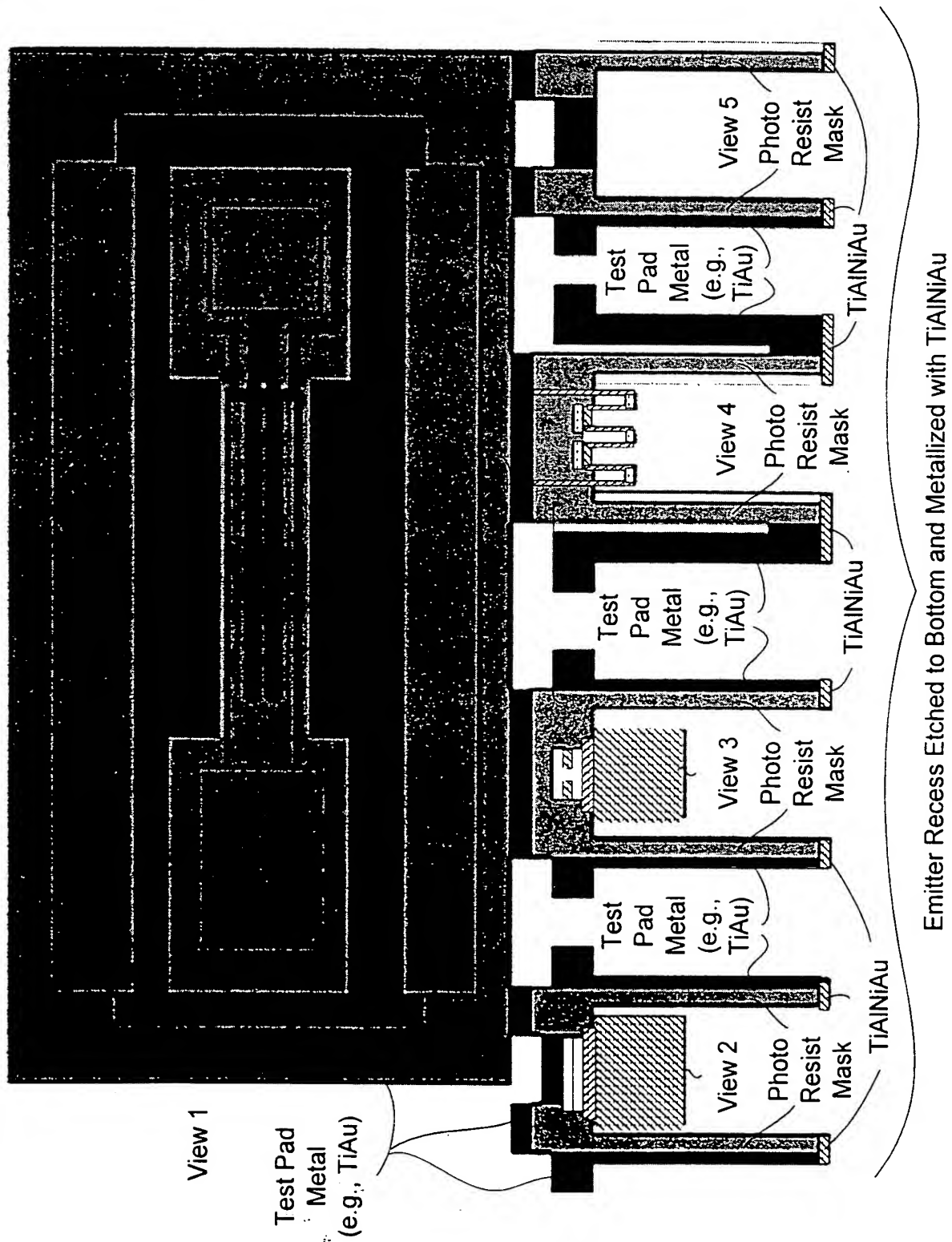
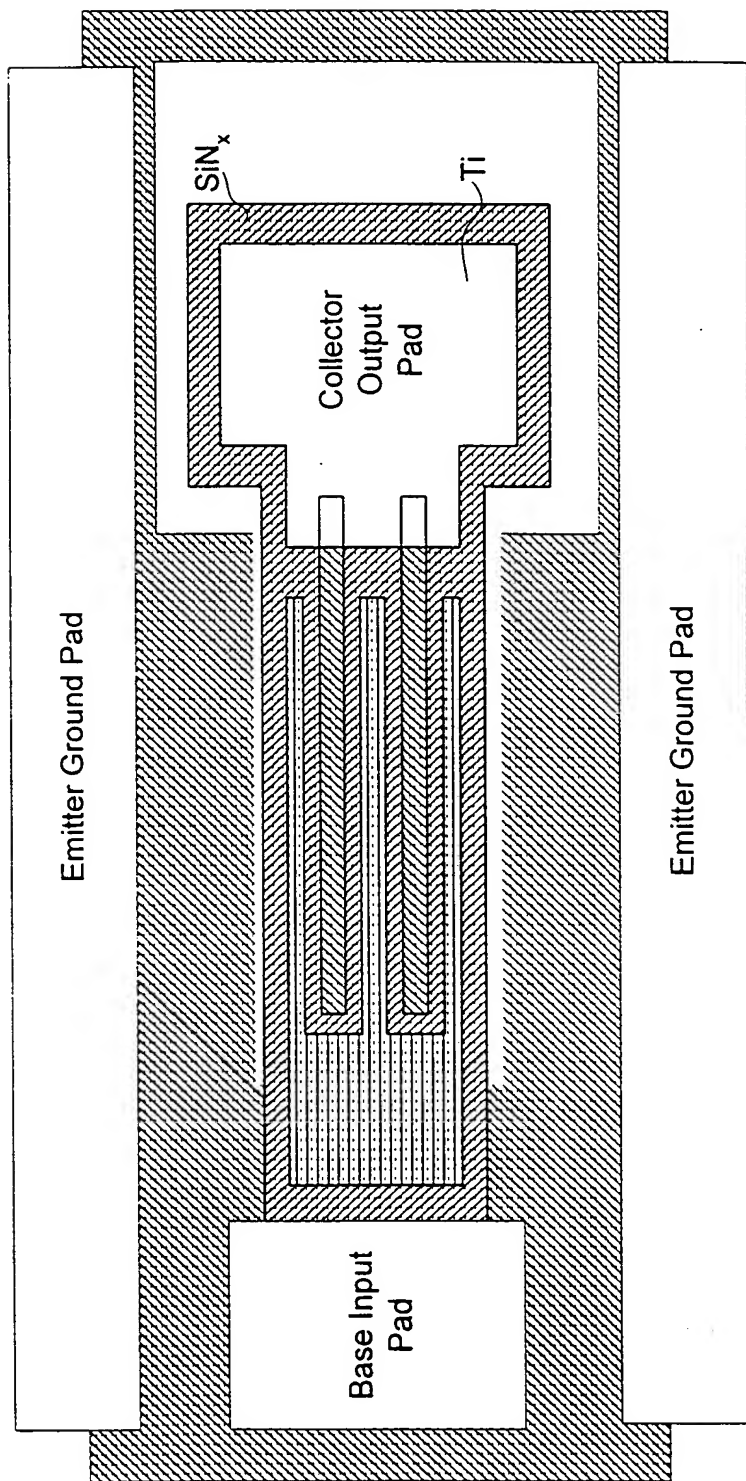


Fig. 3cc

31/43



View 1
 (Final Structure)

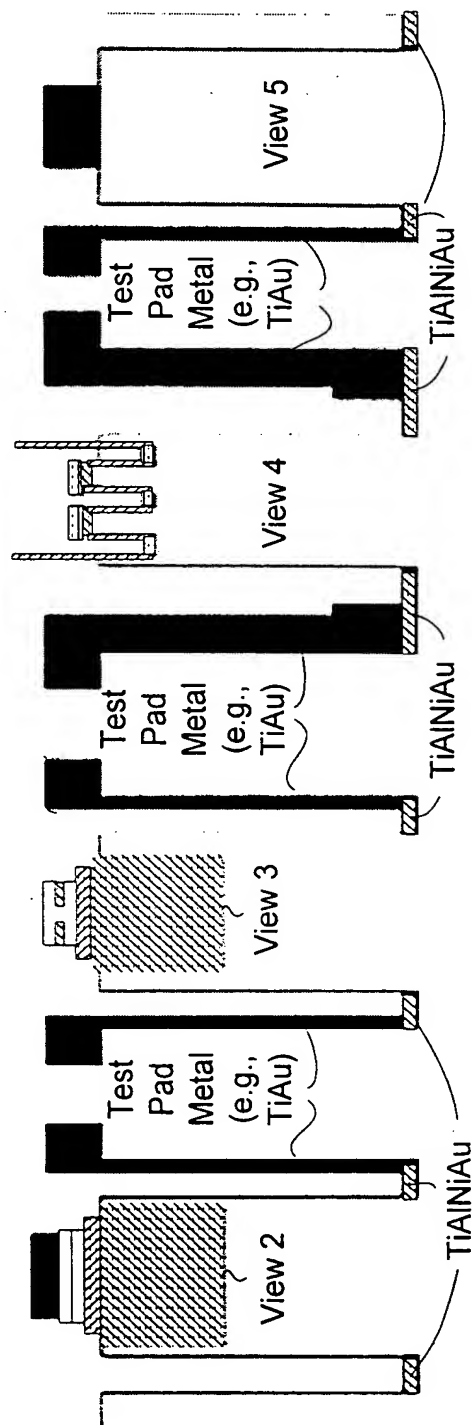


Fig. 3dd

View 1

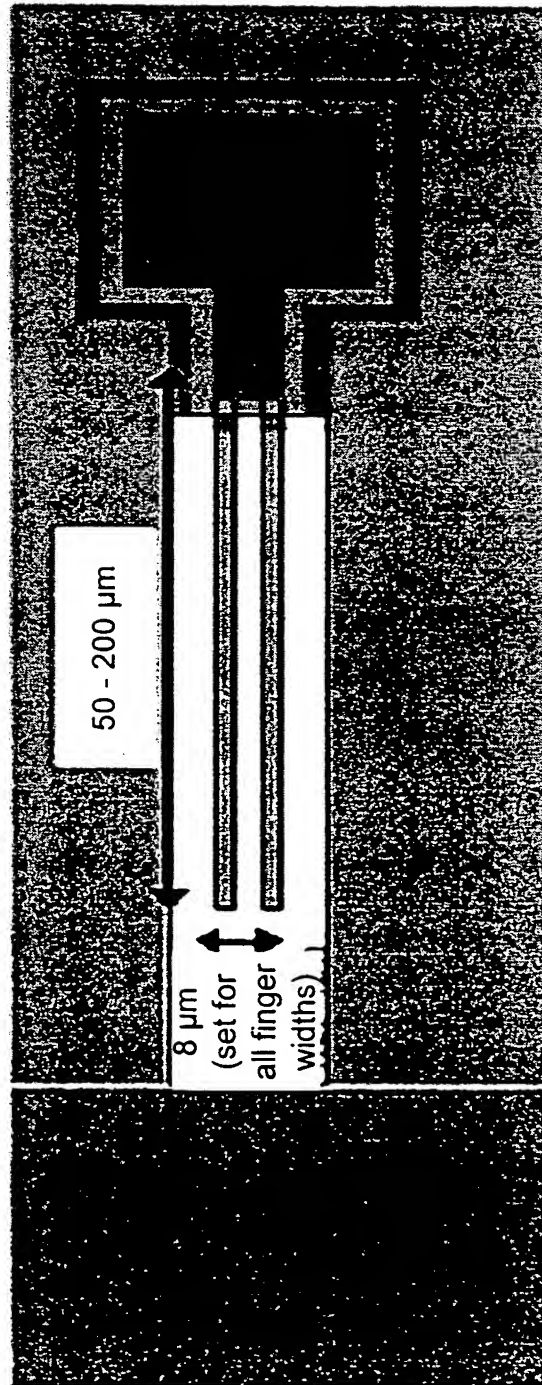


Fig. 4

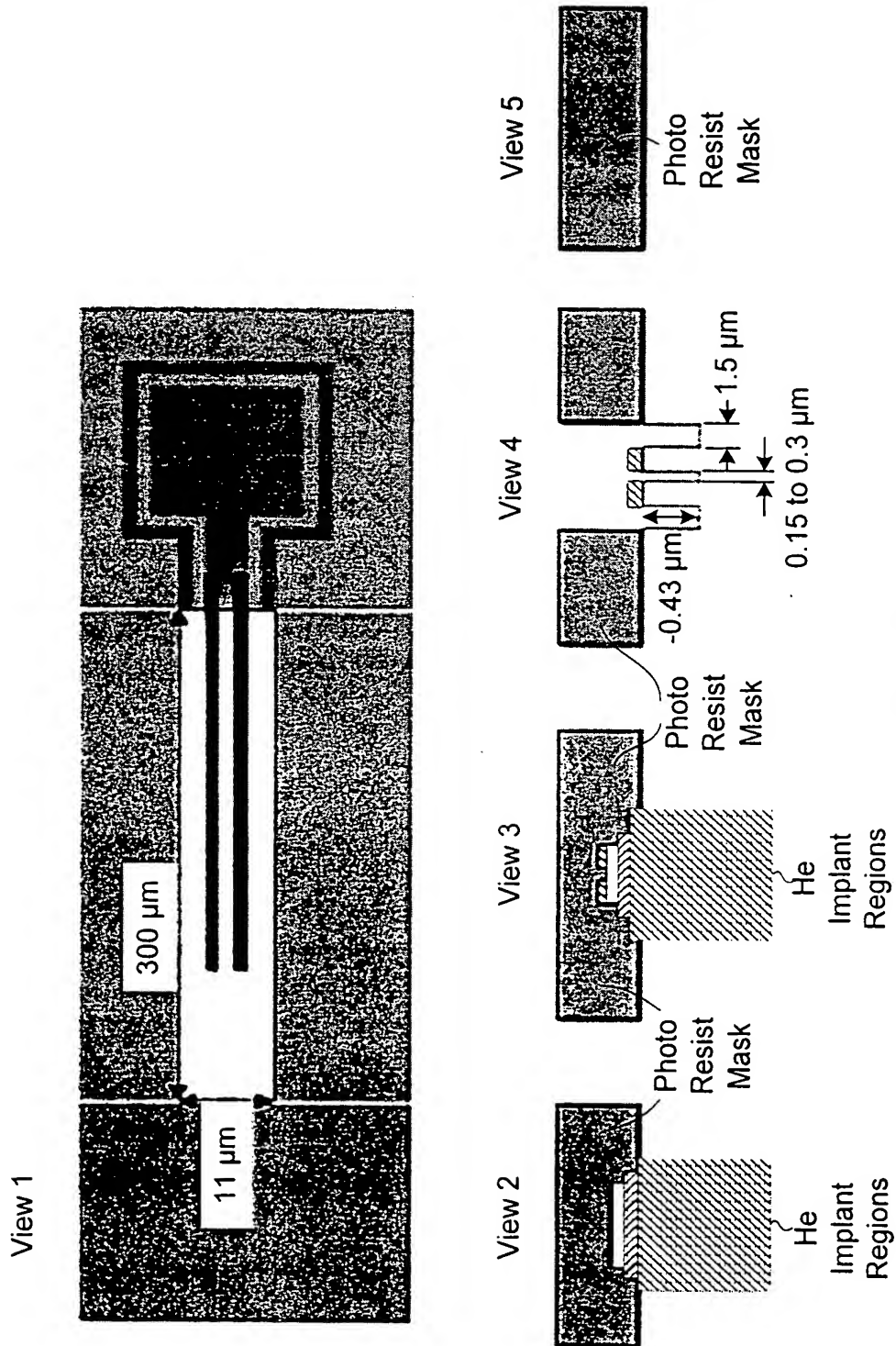


Fig. 5a

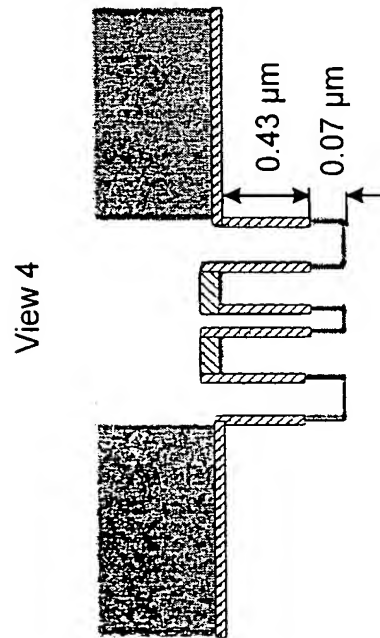


Fig. 5b

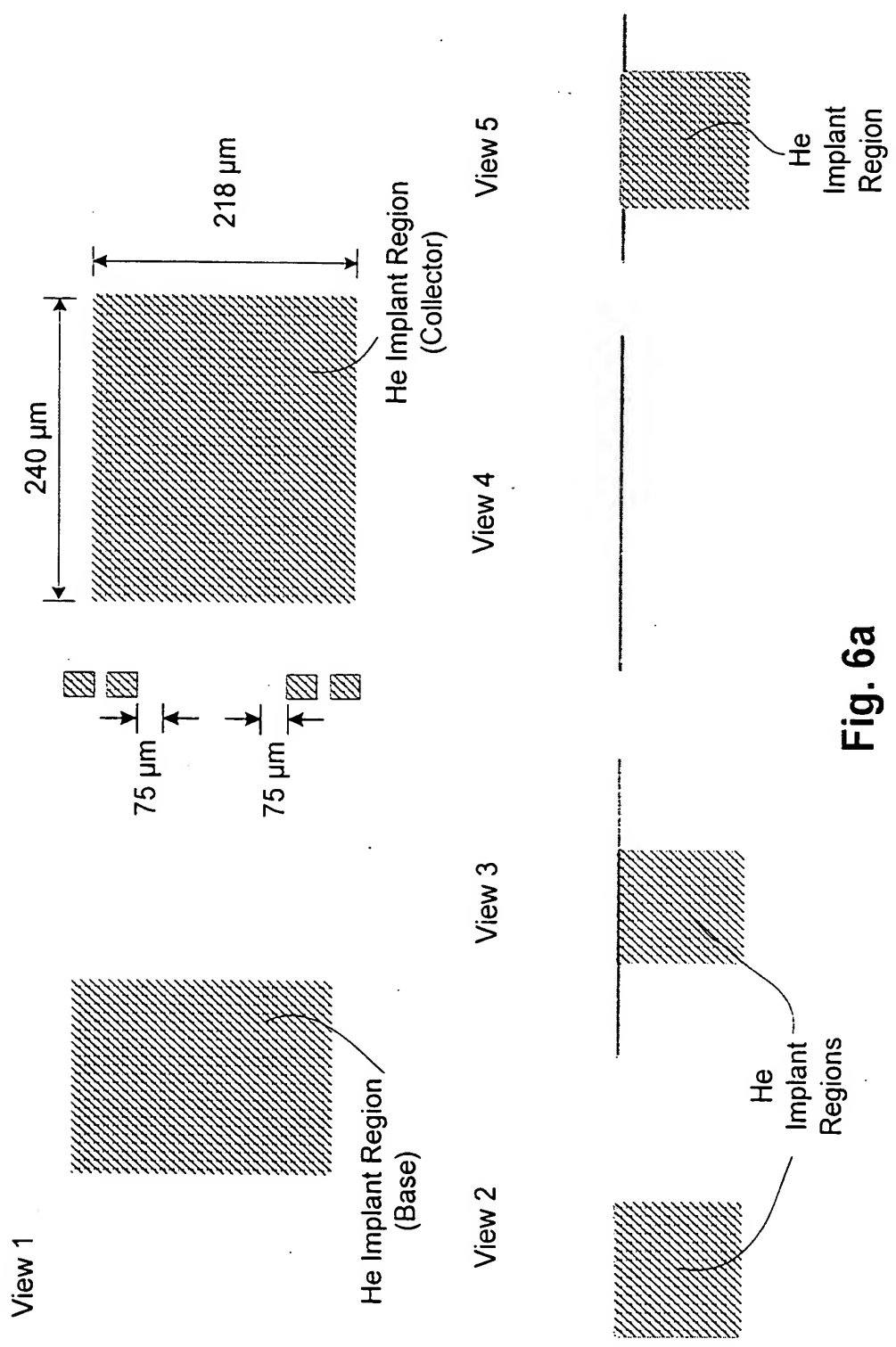


Fig. 6a

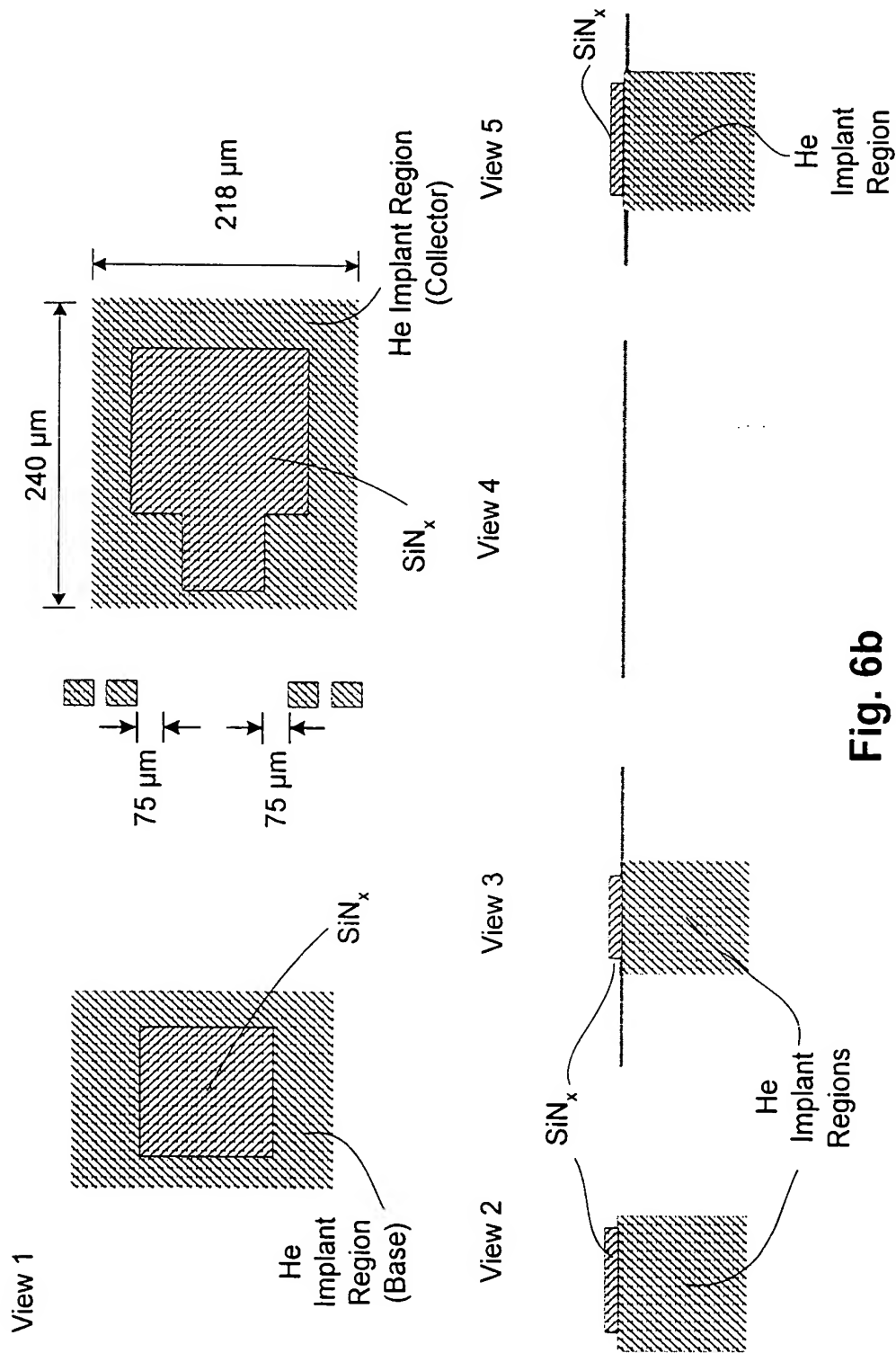


Fig. 6b

37/43

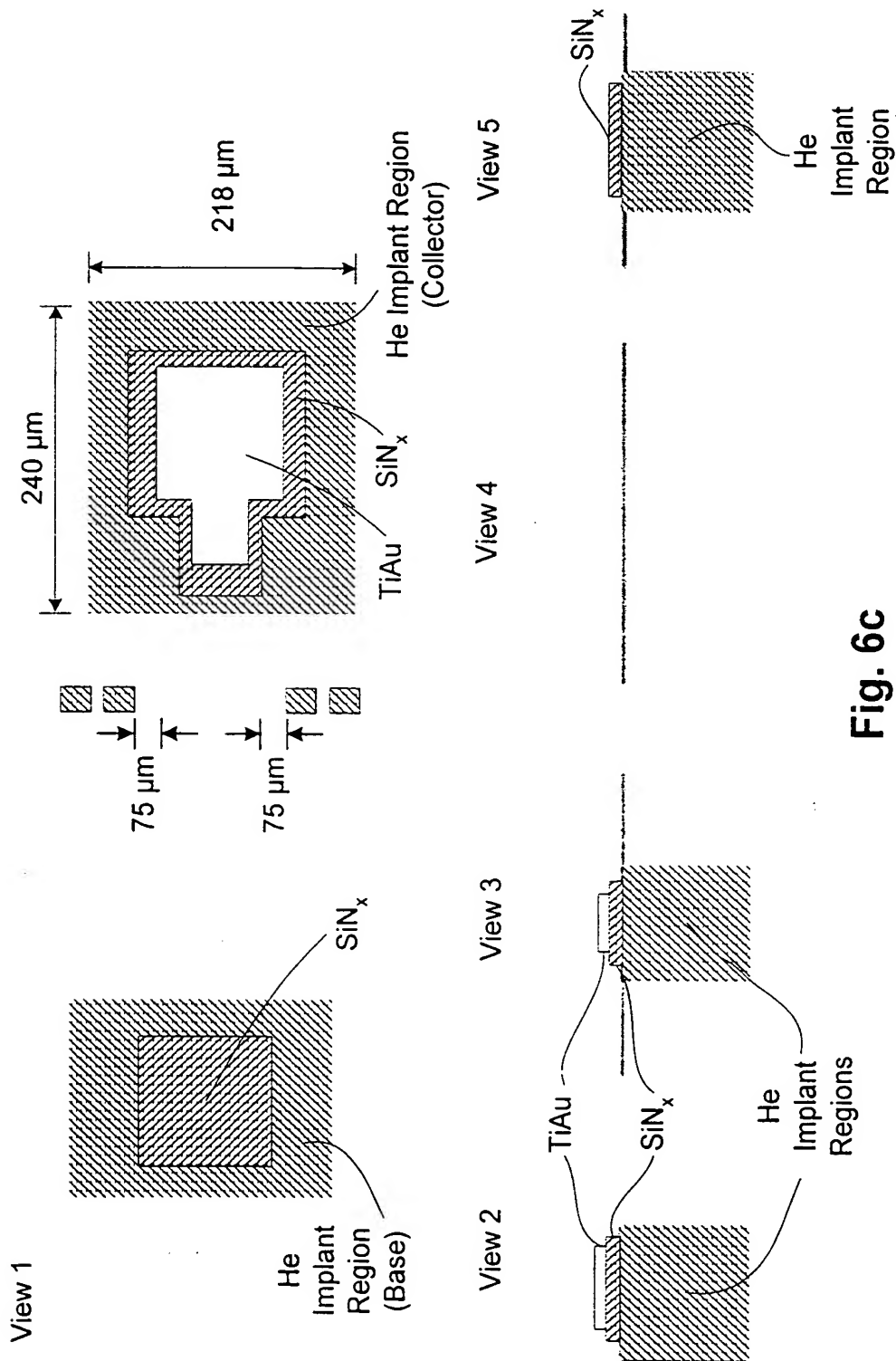


Fig. 6c

38/43

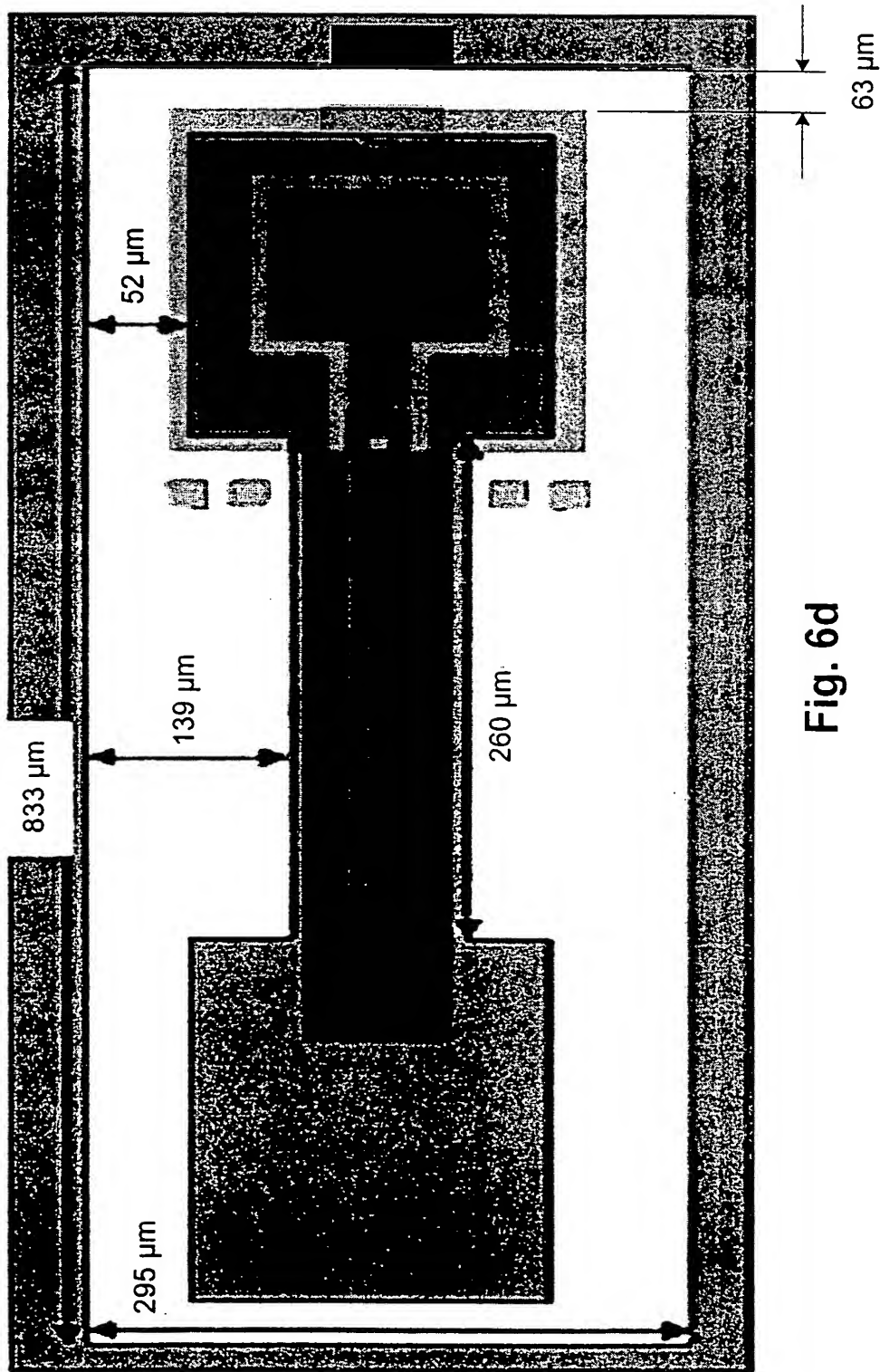


Fig. 6d

View 1

39/43

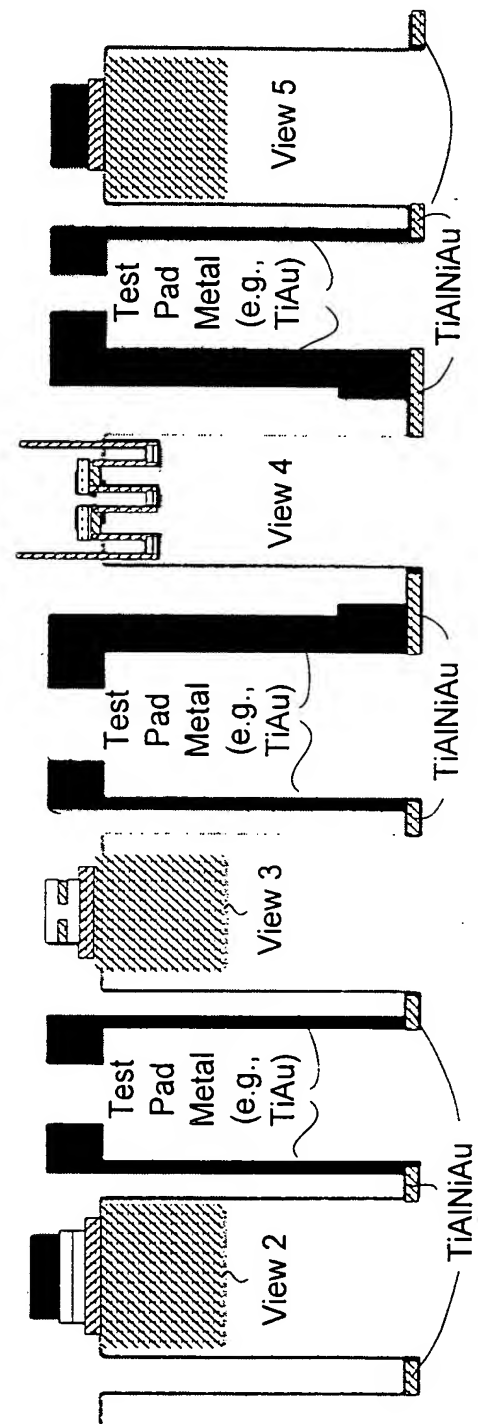
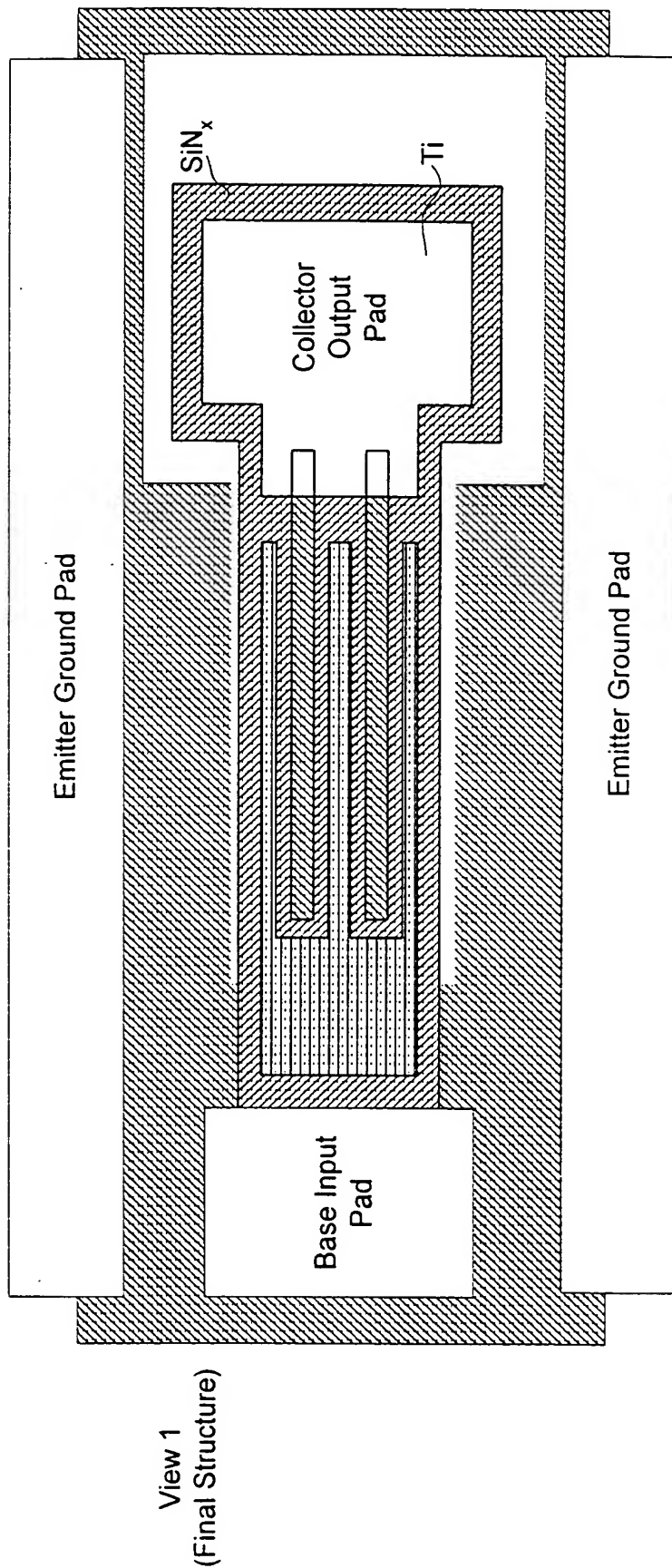


Fig. 6e

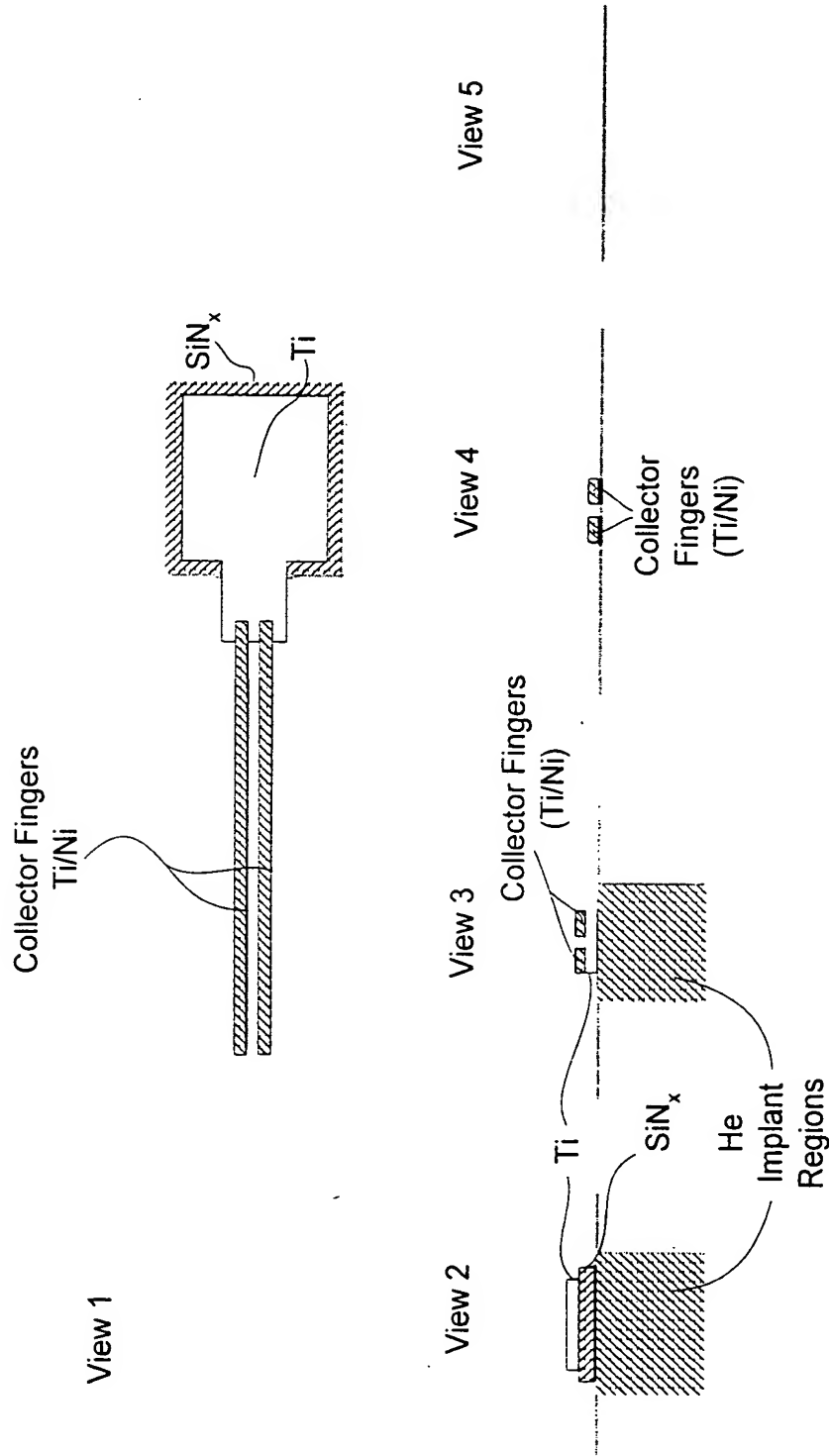


Fig. 7

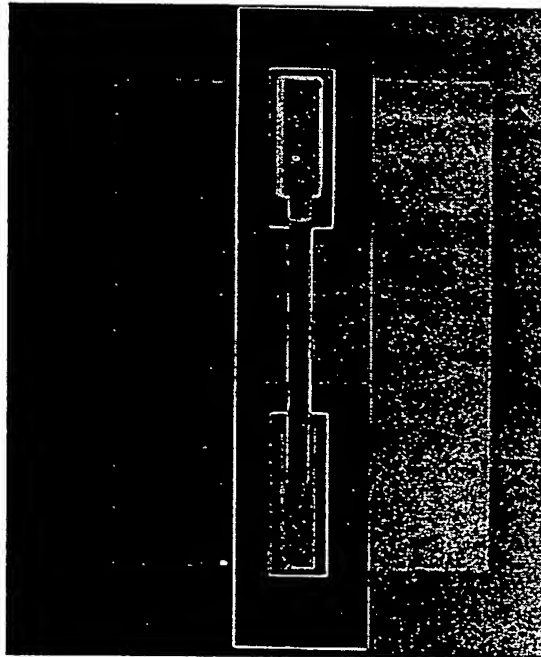


Fig. 8

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PCT - Customer # 42716

42/43

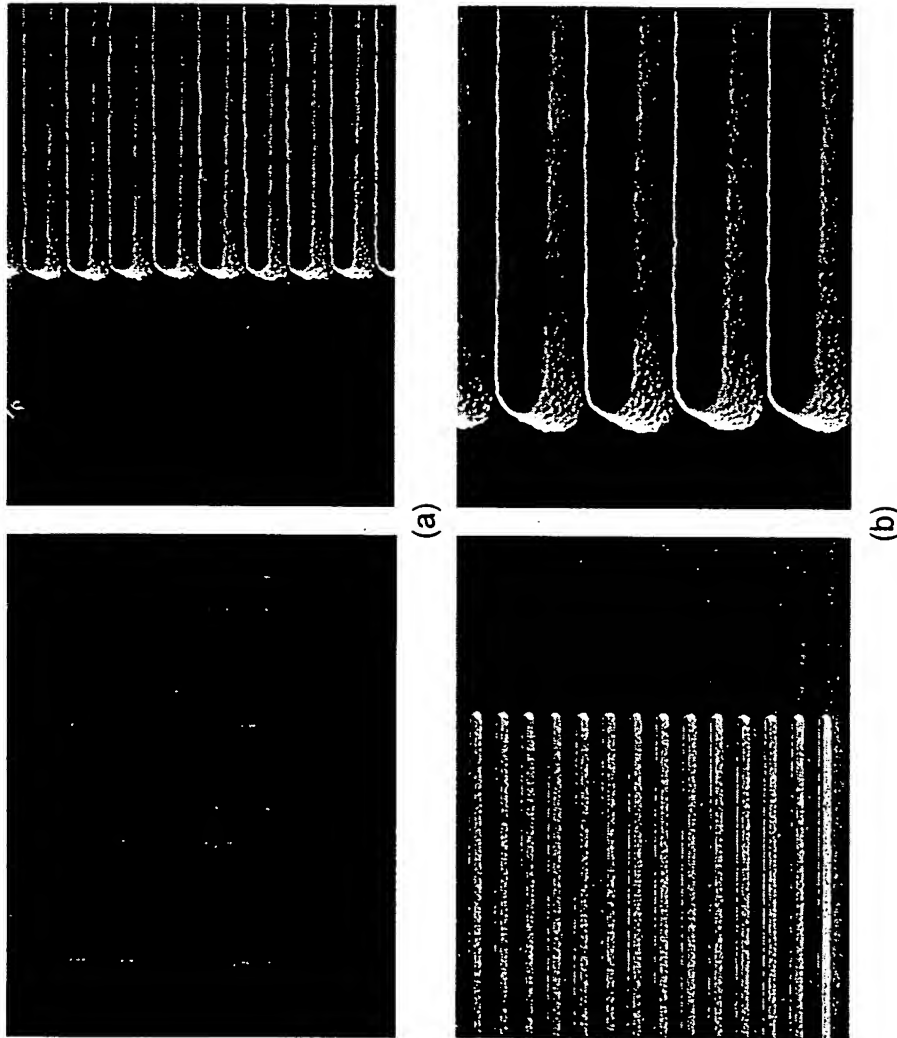


Fig. 9

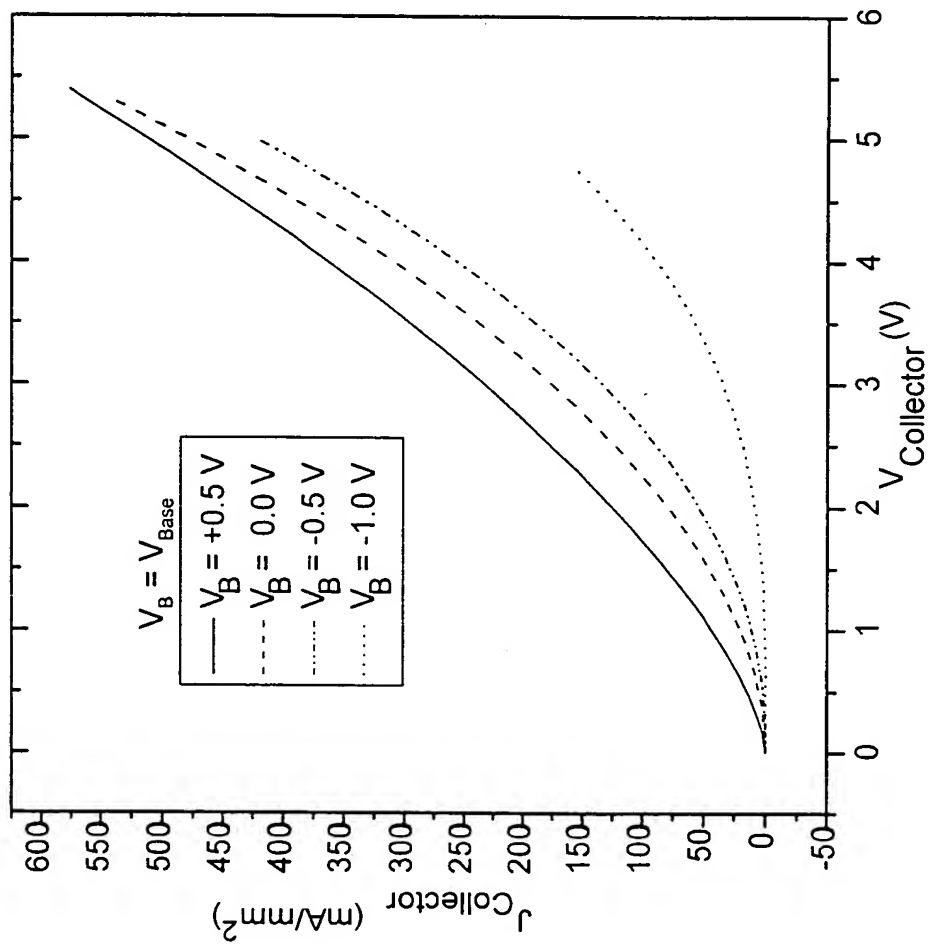


Fig. 10

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